FIG. 1A

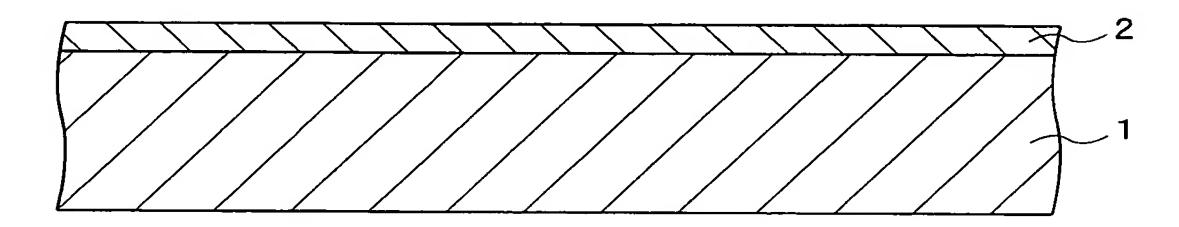


FIG. 1B

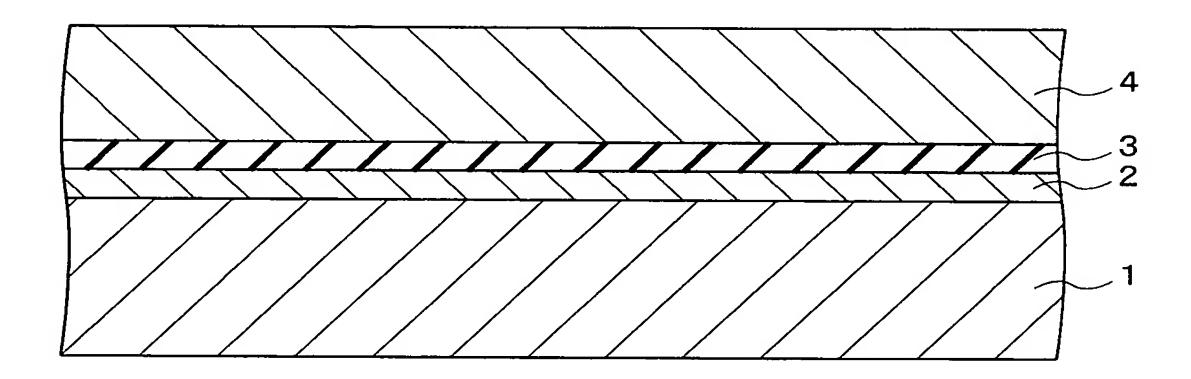


FIG. 1C

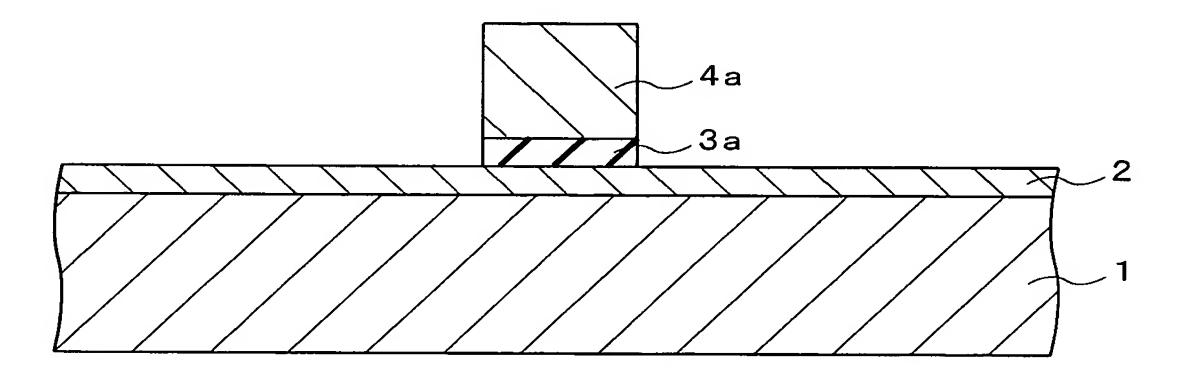


FIG. 2A

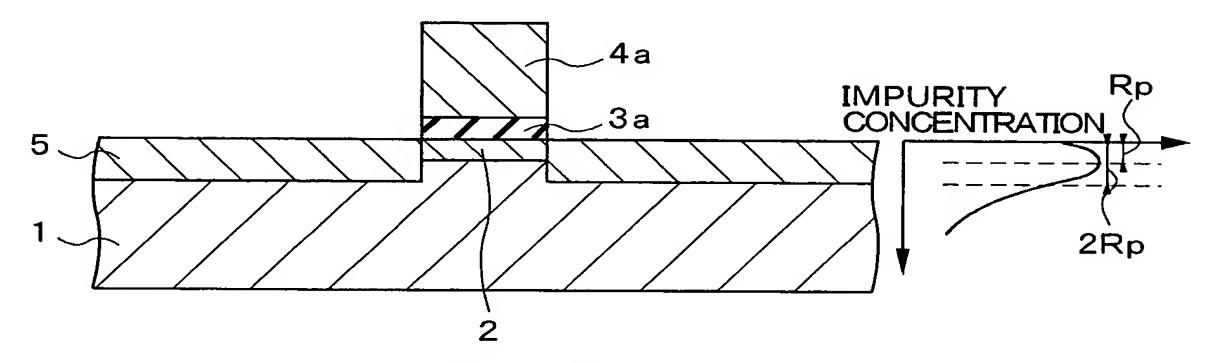


FIG. 2B

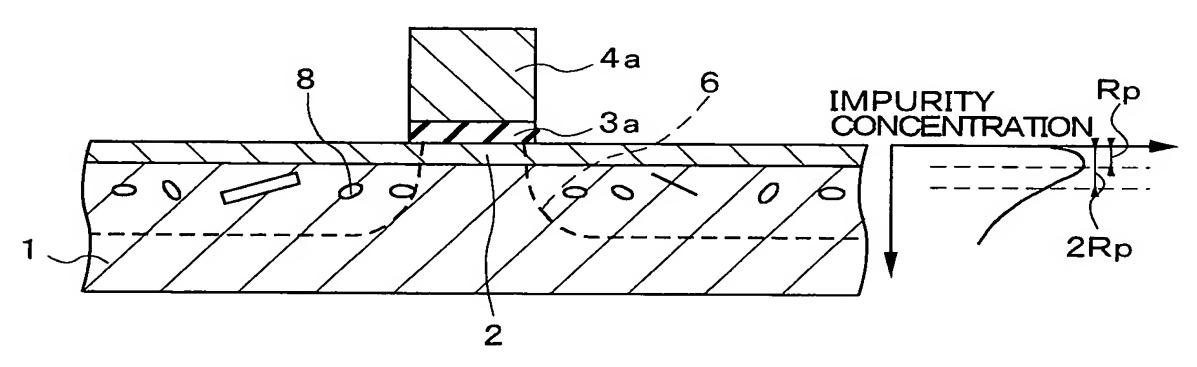
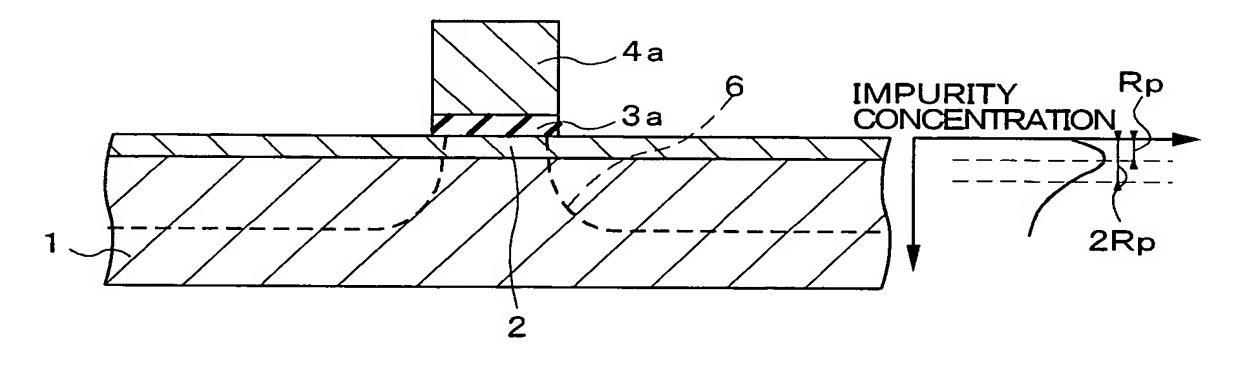


FIG. 2C



Title: MIS-TYPE FIELD-EFFEÇT

TRANSISTOR

FIG. 3A

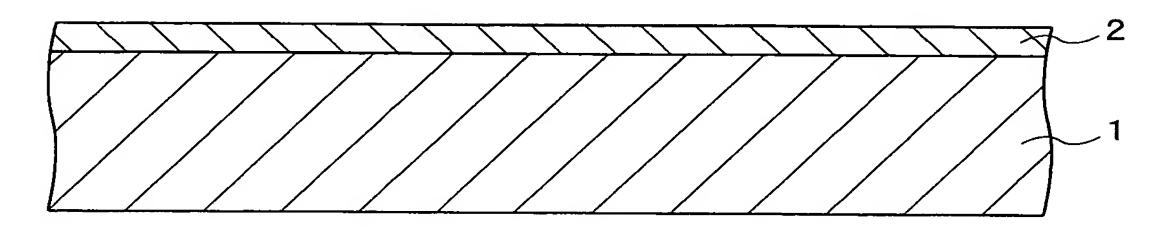


FIG. 3B

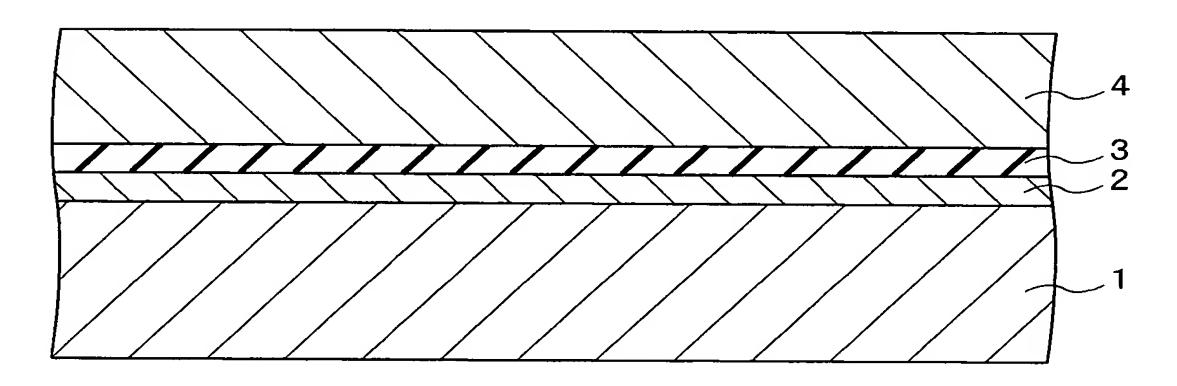
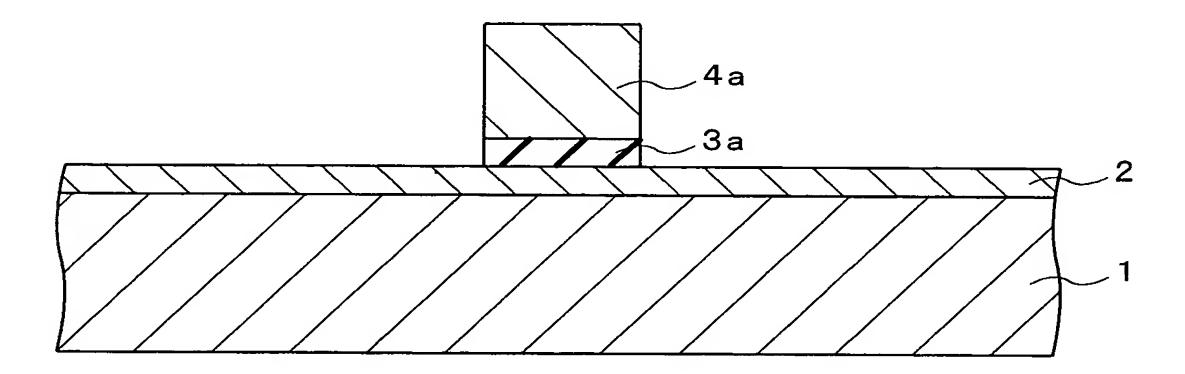


FIG. 3C



THE: MIS-1 YPE FIELD-EFFECT

**TRANSISTOR** 

FIG. 4A

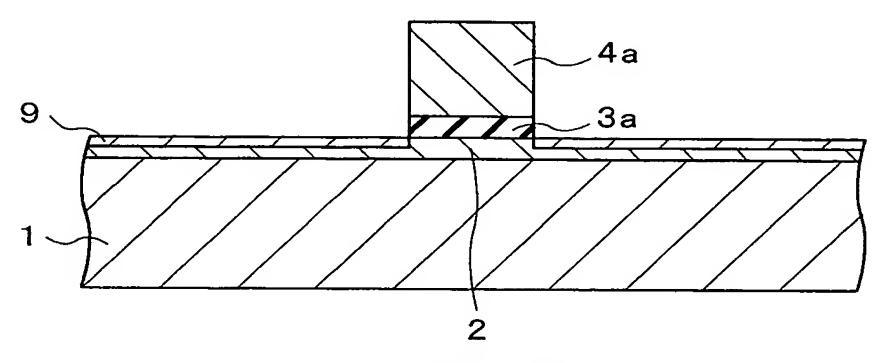


FIG. 4B

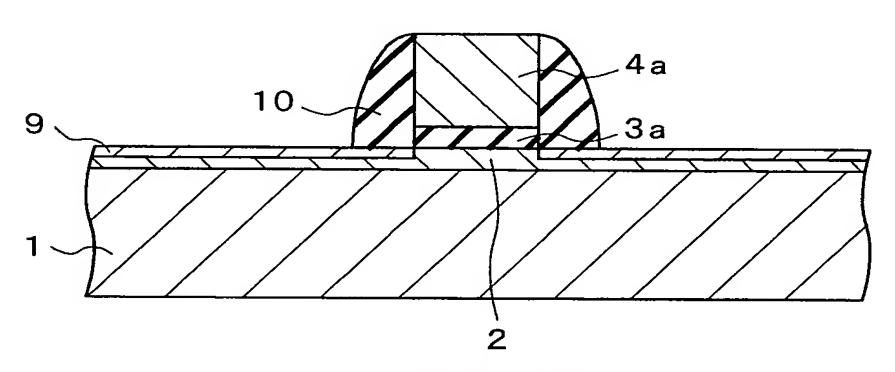


FIG. 4C

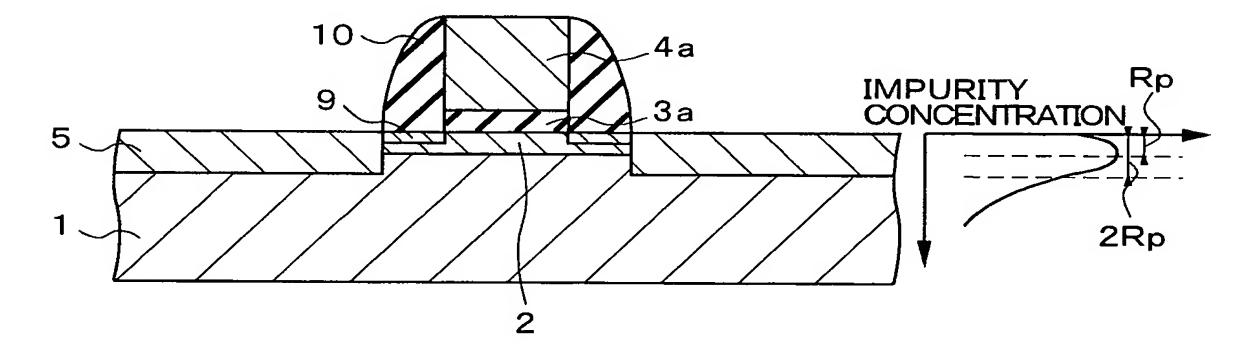


FIG. 5A

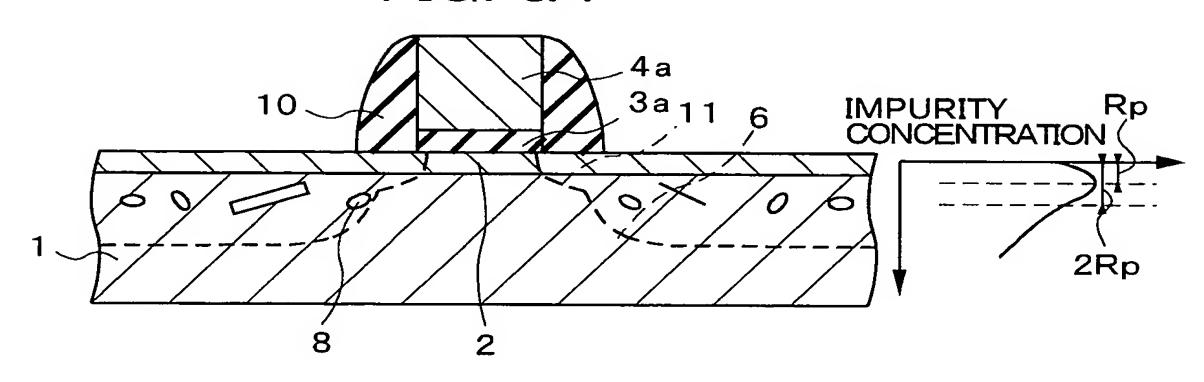


FIG. 5B

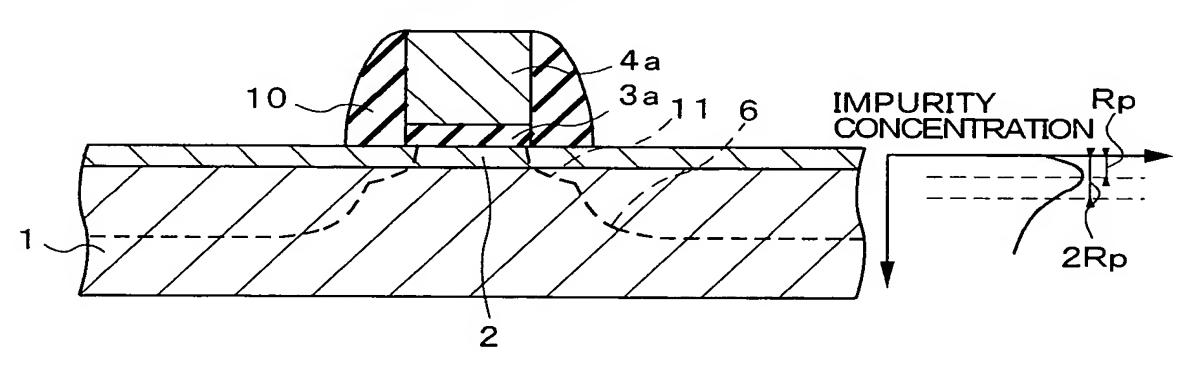


FIG. 6

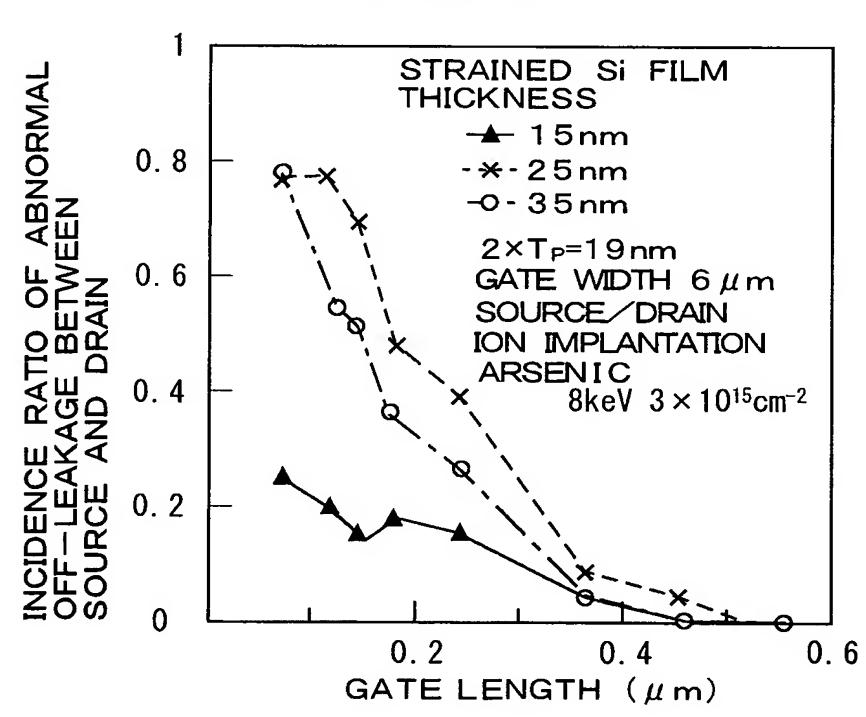


FIG. 7A

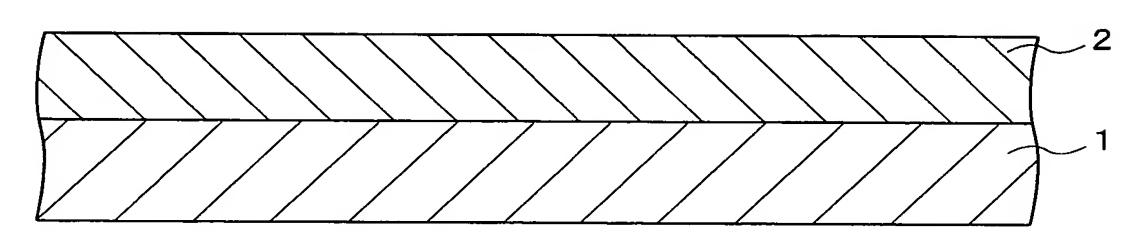


FIG. 7B

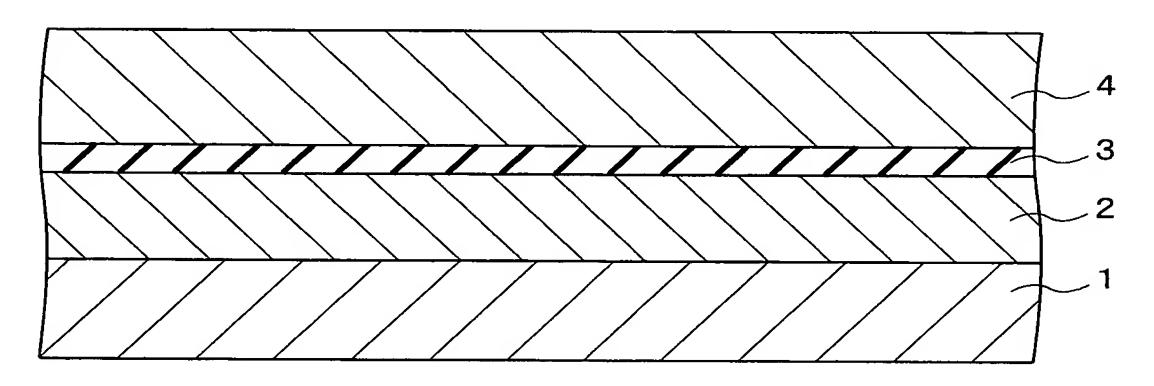
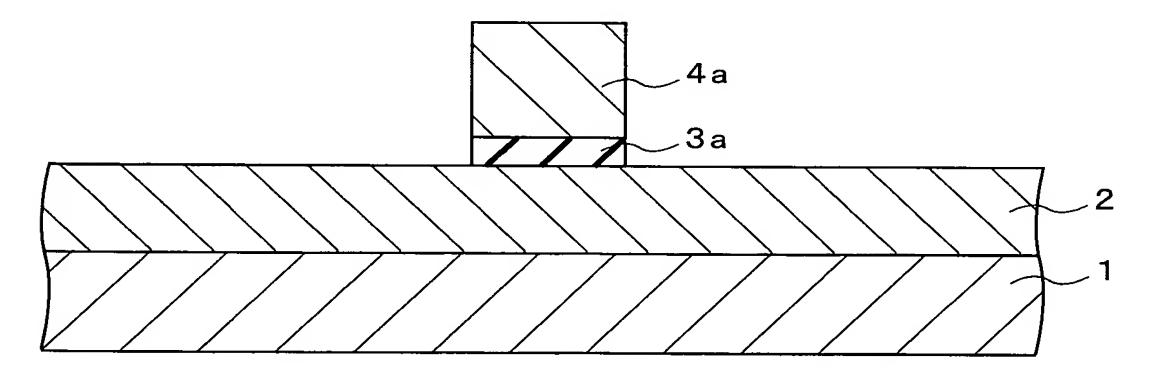


FIG. 7C



The: Mis-1 Yee FIELD-EFFECT

TRANSISTOR

FIG. 8A

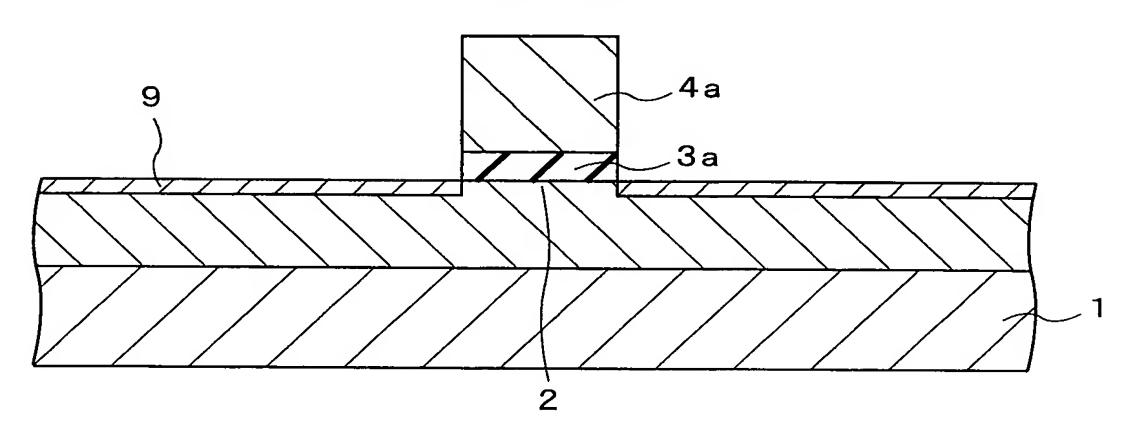


FIG. 8B

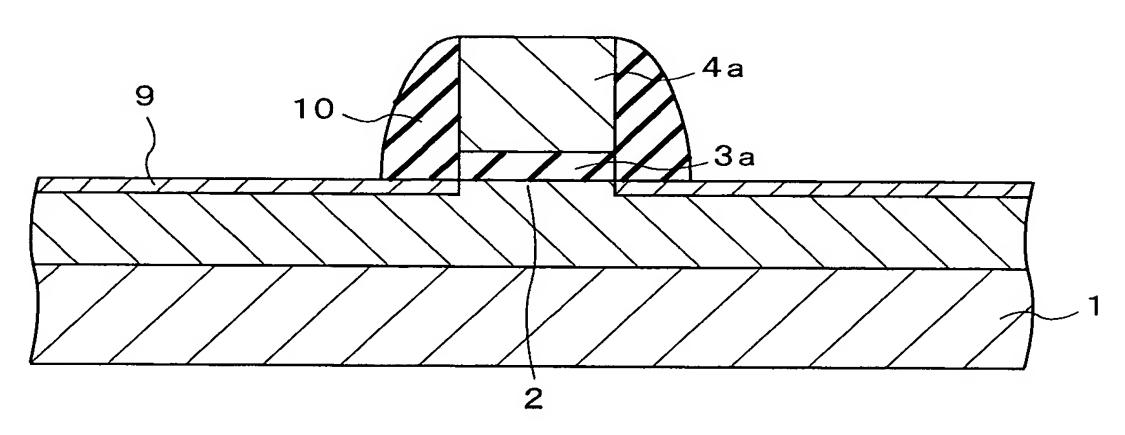
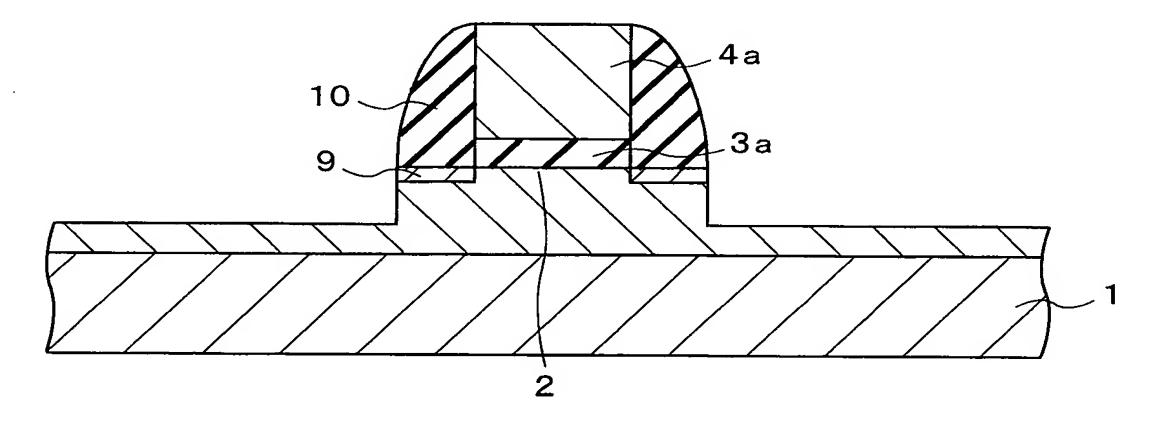


FIG. 8C



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TRANSISTOR

FIG. 9A

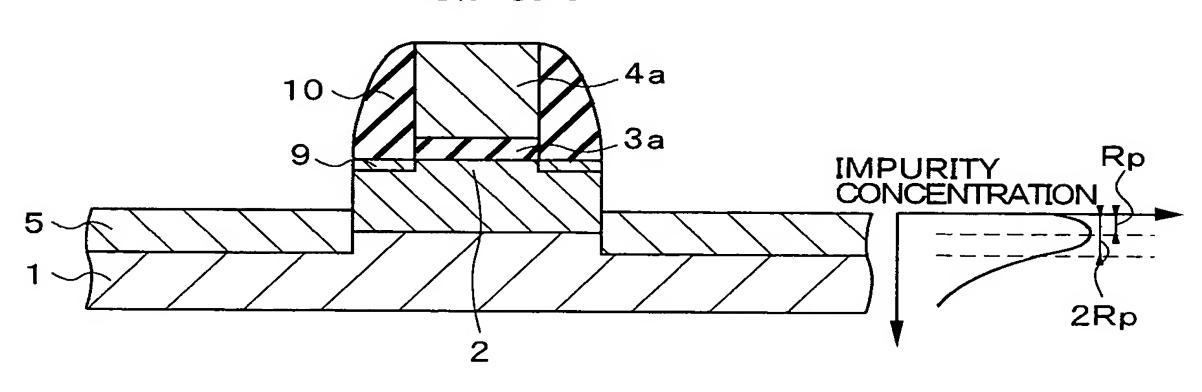


FIG. 9B

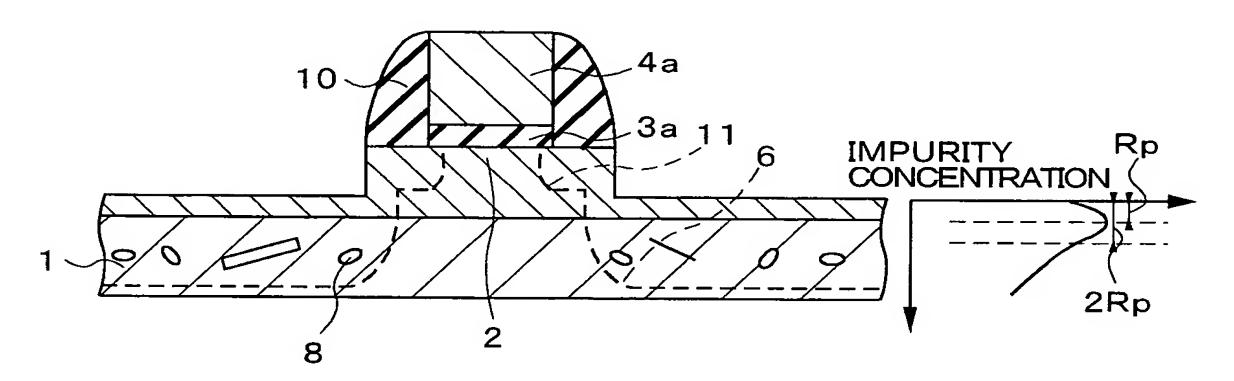


FIG. 9C

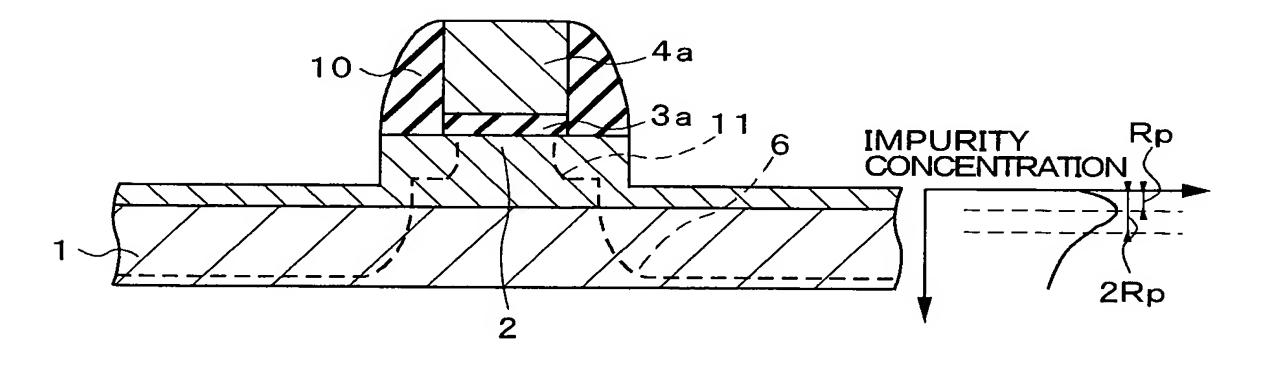


FIG. 10A

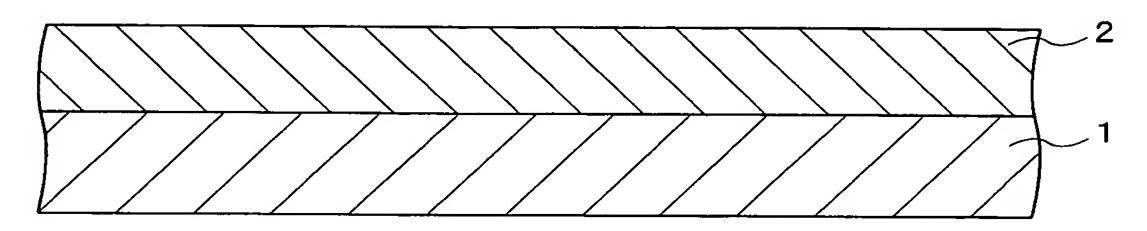


FIG. 10B

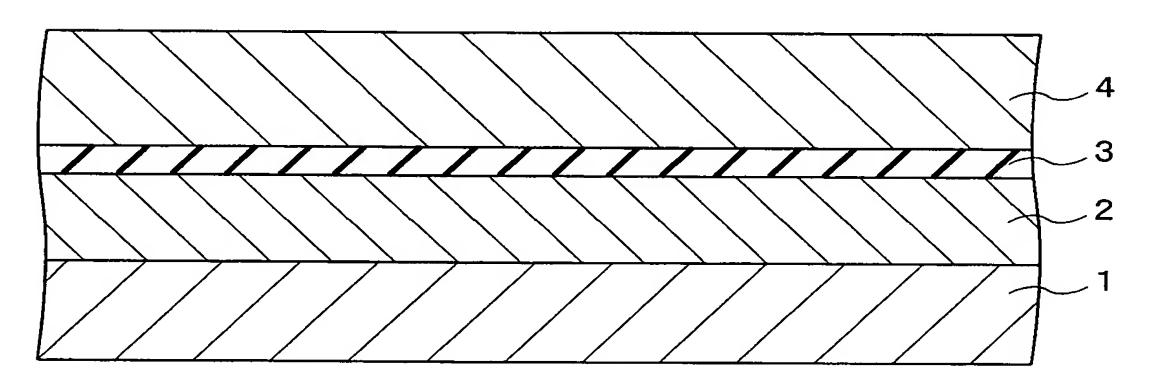
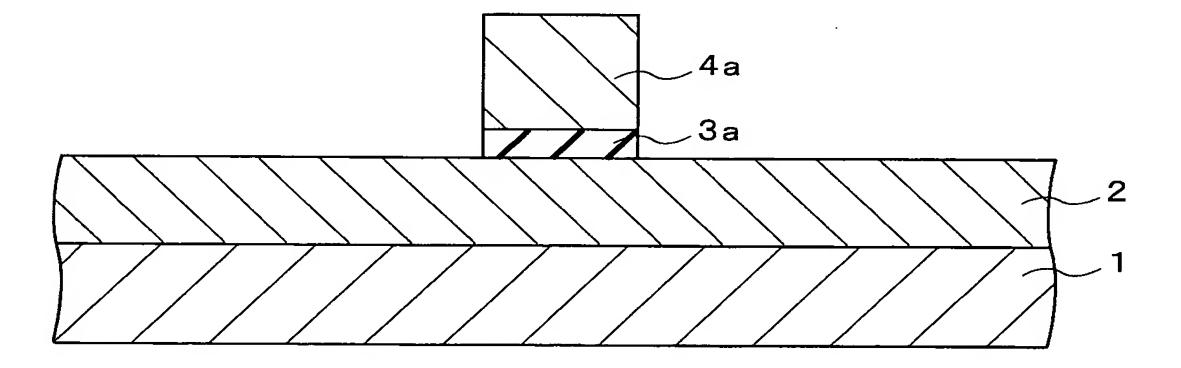
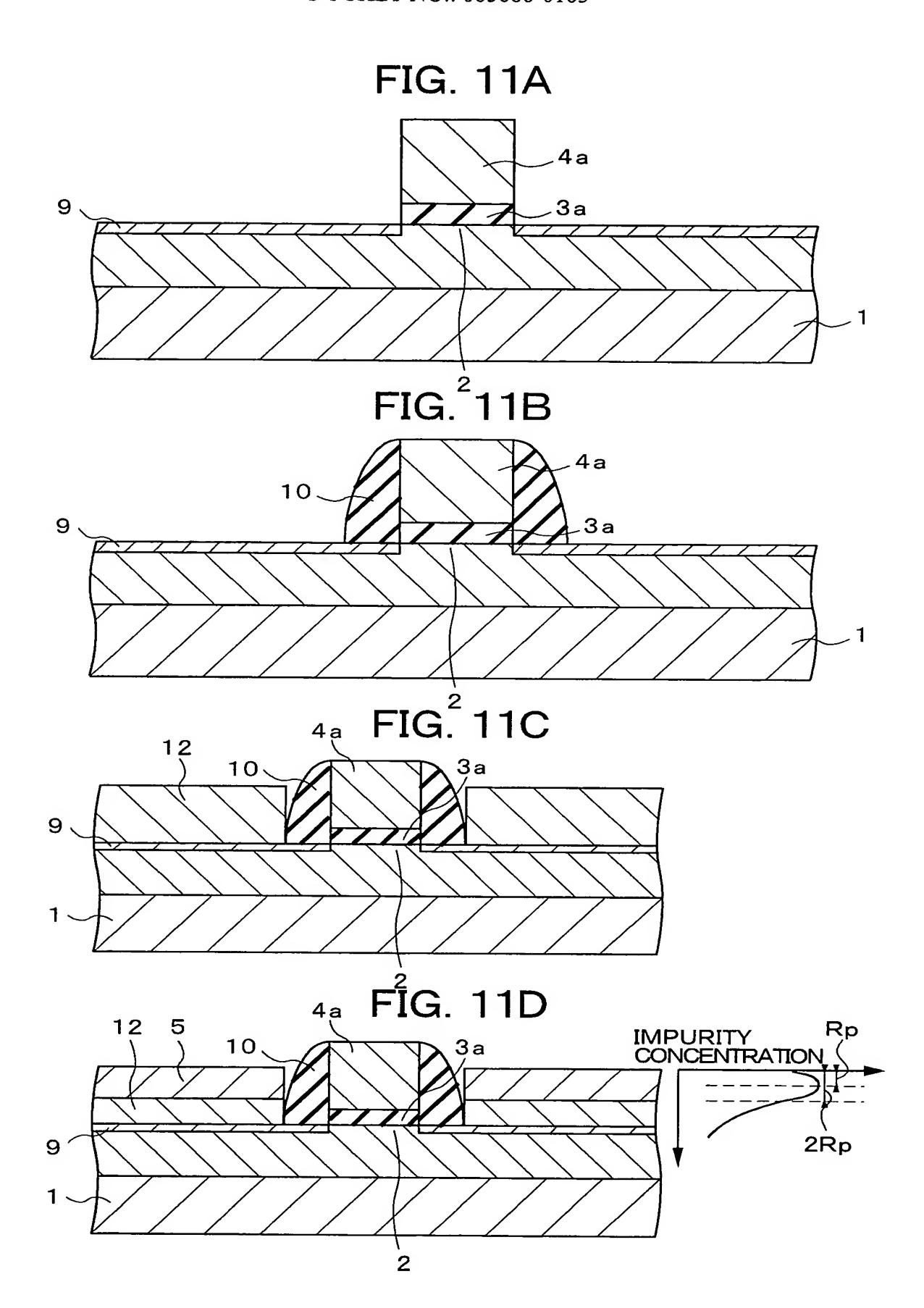
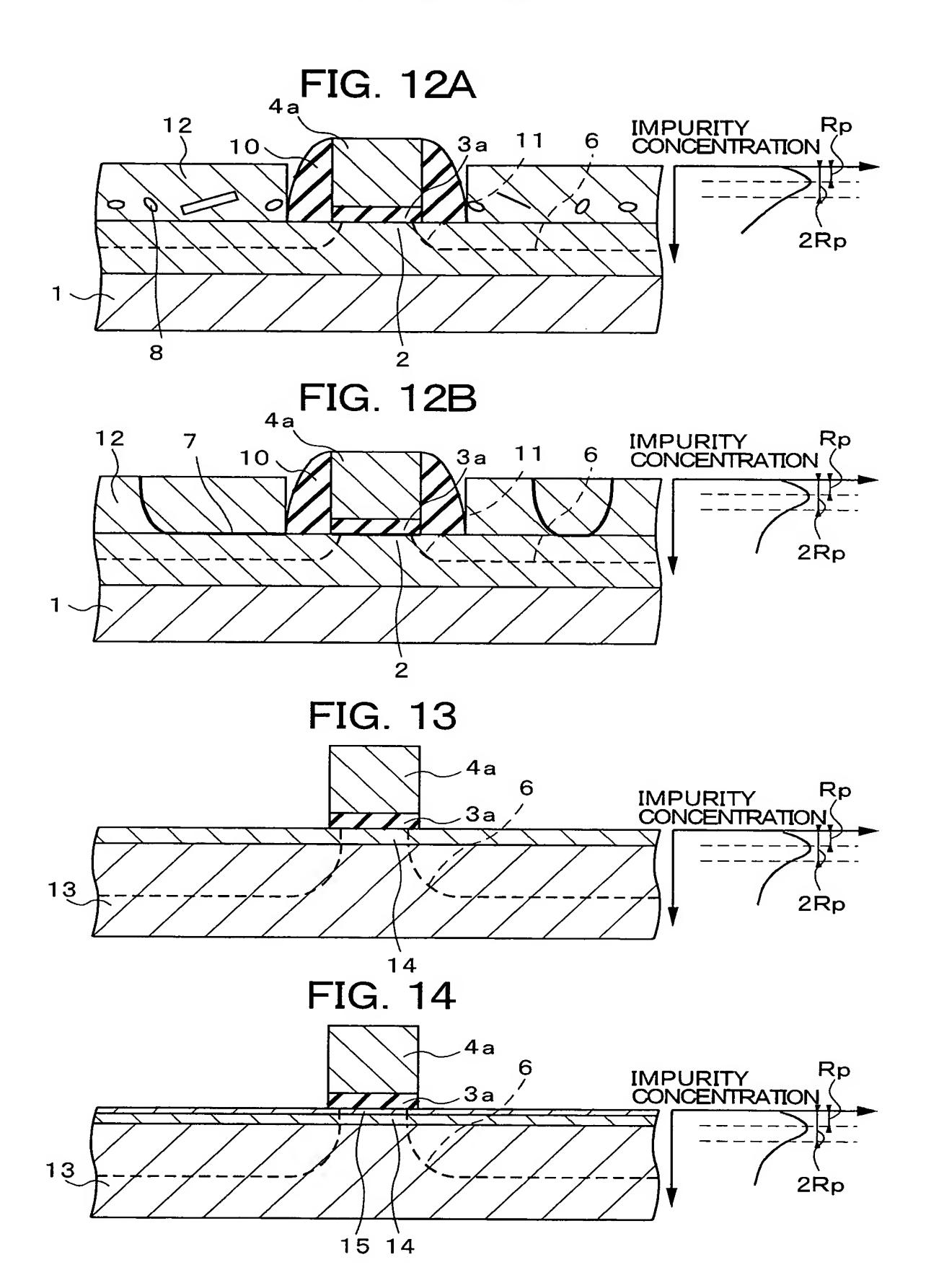


FIG. 10C







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Inventor(s): Kazuya UEJIMA DOCKET NO.: 06\$686-0163

FIG. 15

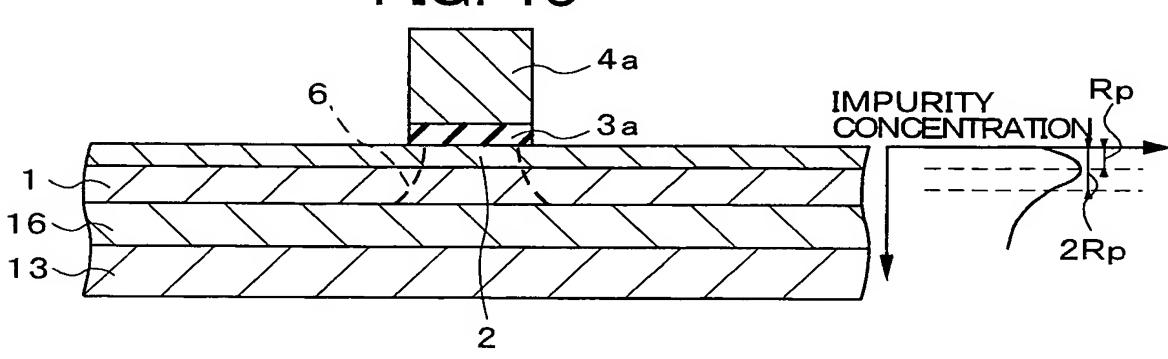


FIG. 16

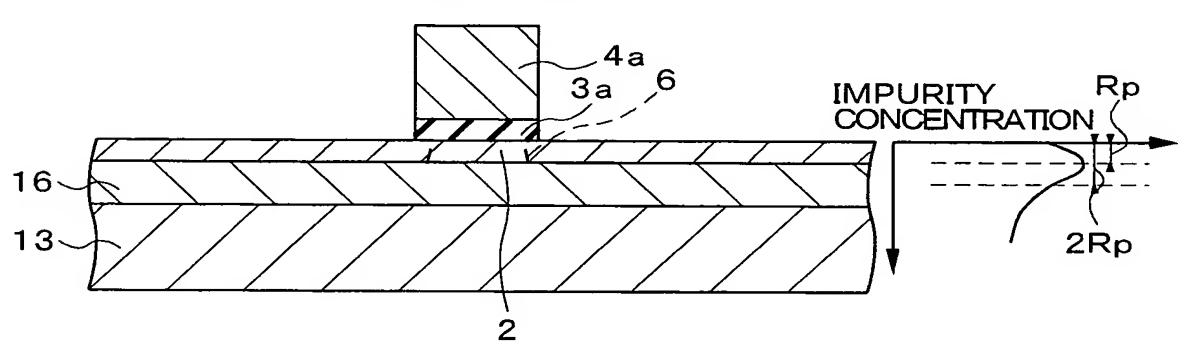
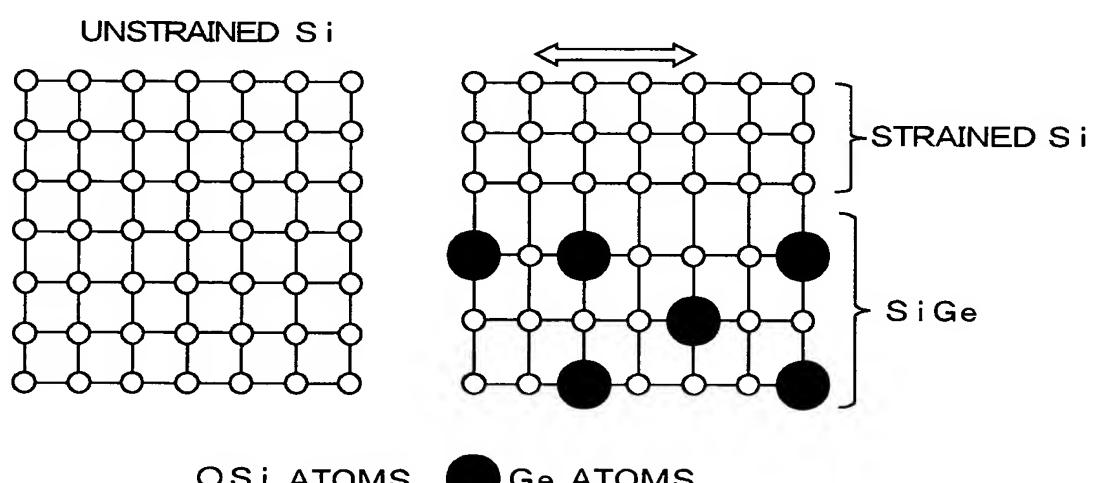


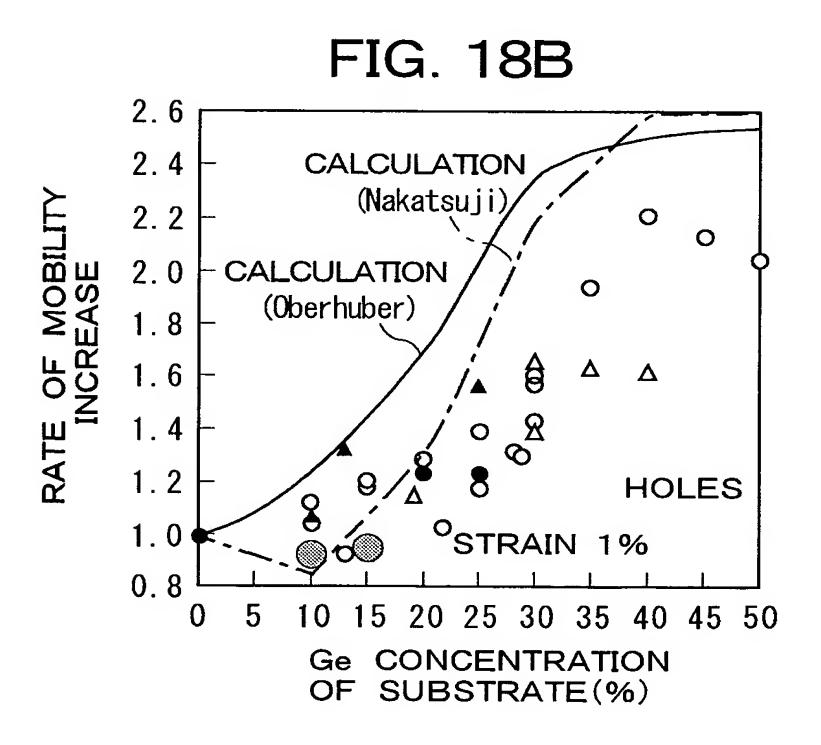
FIG. 17



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Title: MIS-TYPE FIELD-EFFECT TRANSISTOR

FIG. 18A 2.4 **ELECTRON** 2.2 0 RATE OF MOBILITY INCREASE CALCULATION 2.0 (Rashed) P 1.8 0 1.6 CALCULATION (TAKAGI) 1.4 1.2 1.0¢ STRAIN 1% 0.8 5 10 15 20 25 30 35 40 0 Ge CONCENTRATION OF SUBSTRATE(%)



11tle: MIS-TYPE FIELD-EFFECT

TRANSISTOR

FIG. 19A

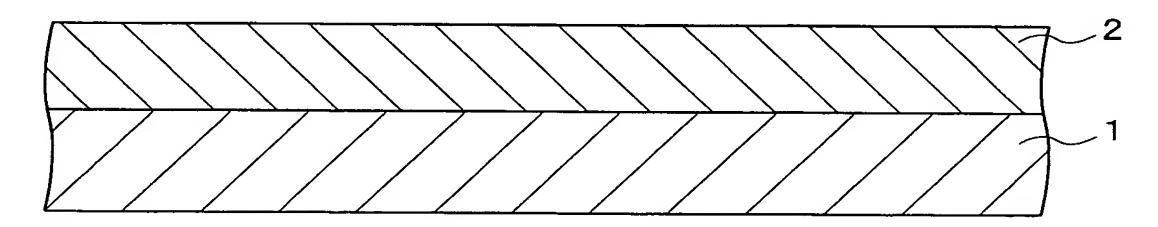


FIG. 19B

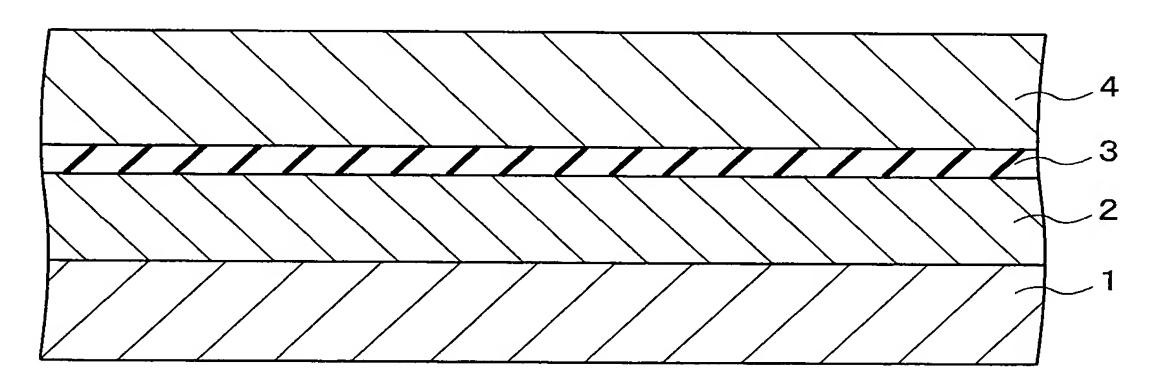
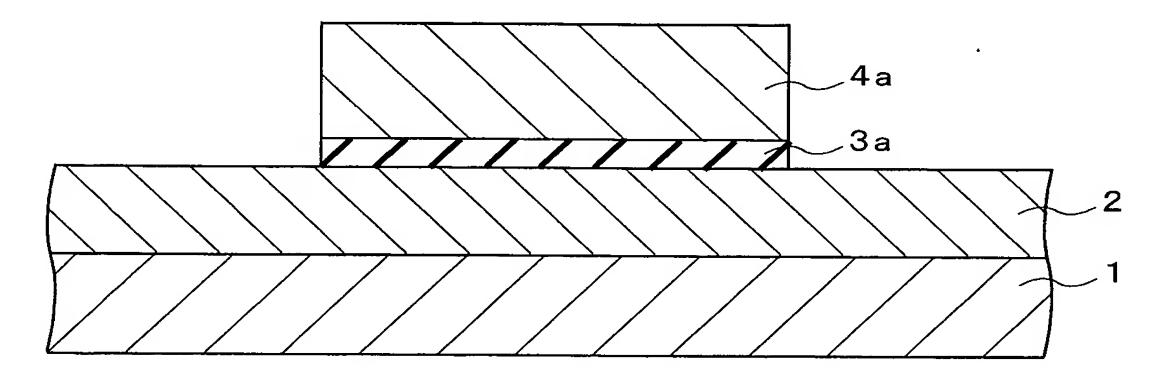


FIG. 19C



11tie: Mis-1 Yrd Fiblu-Errau-

TRANSISTOR

FIG. 20A

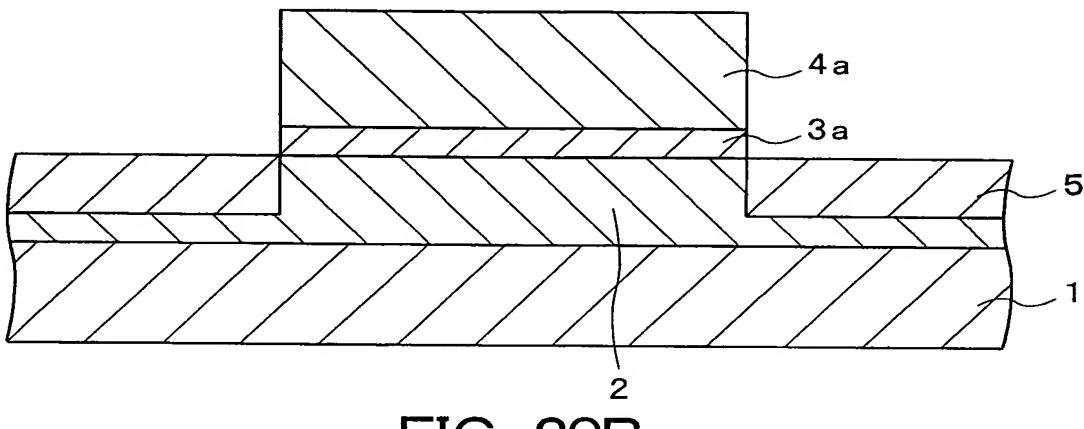


FIG. 20B

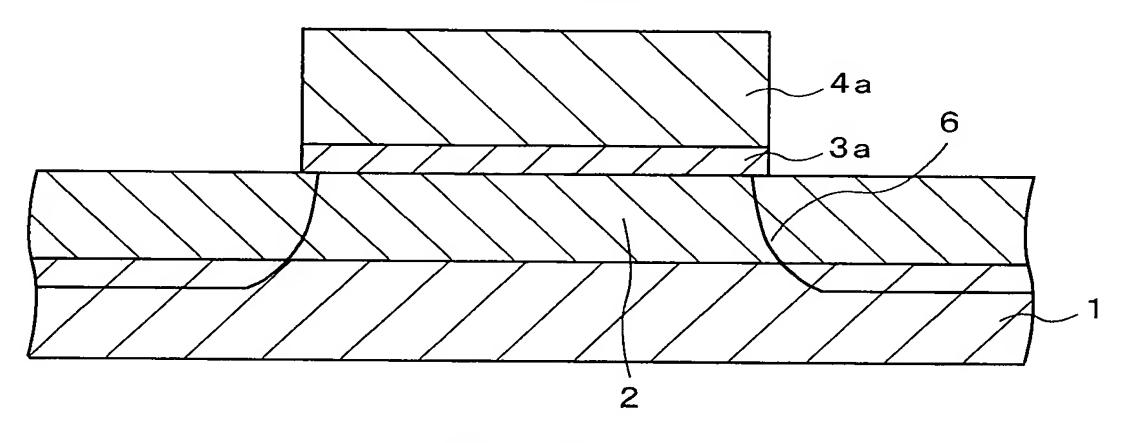
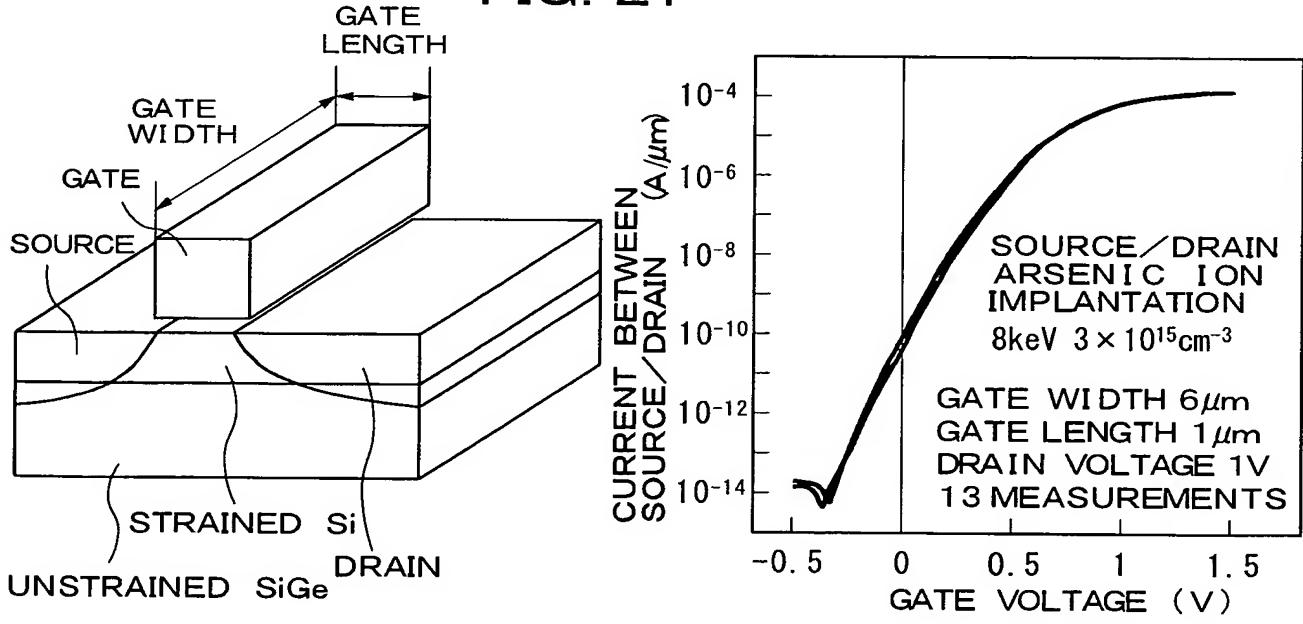
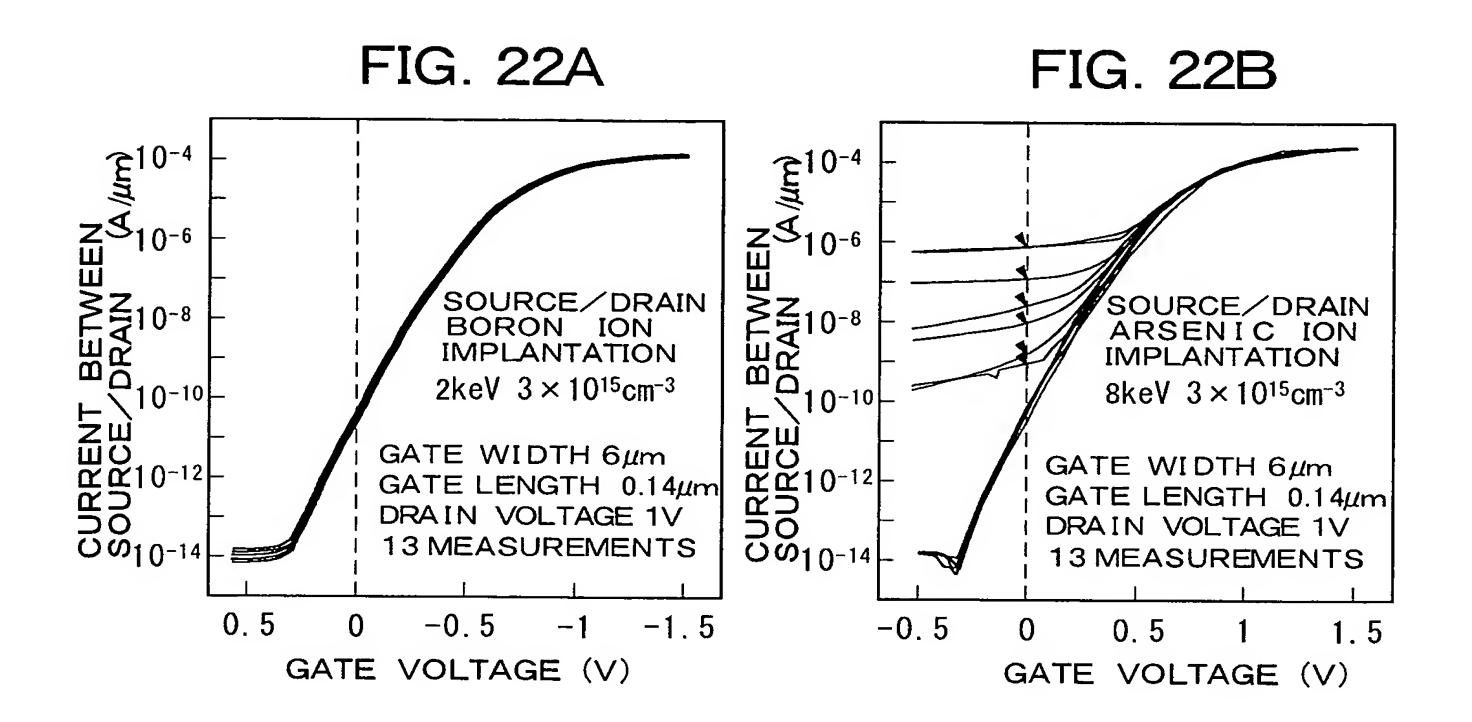
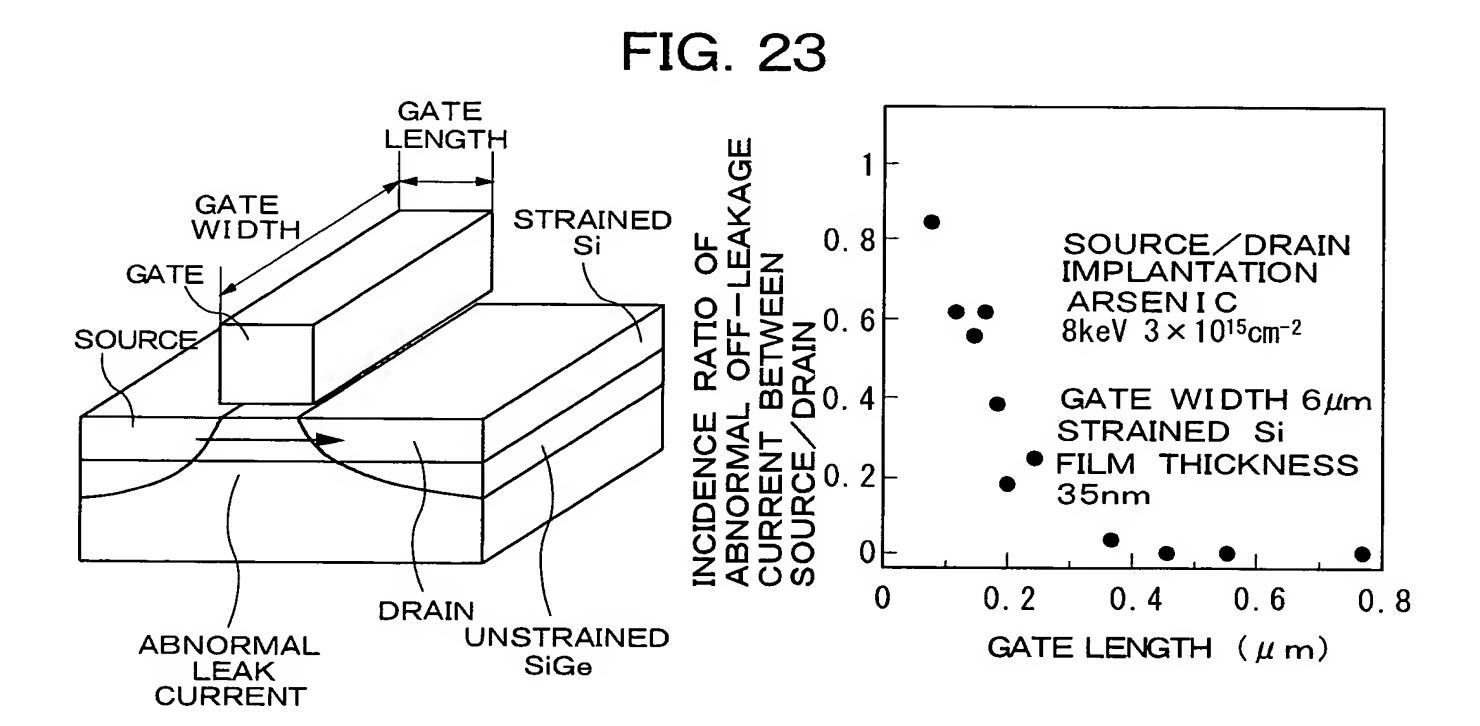


FIG. 21



11tle: MIS-1 YPE FIELD-EFFECT
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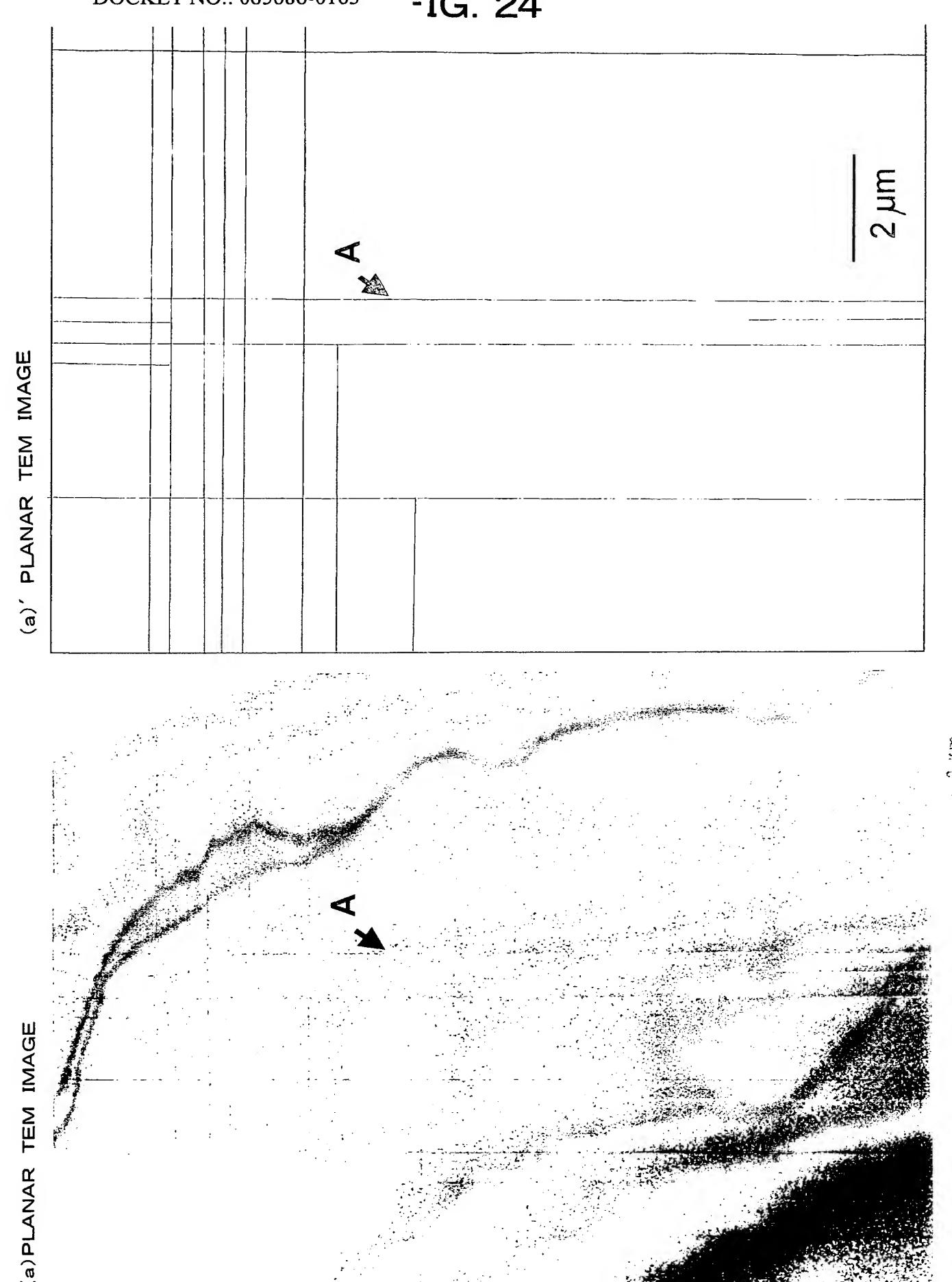


THE: MIS-I YEE FIELD-EFFECT

TRANSISTOR

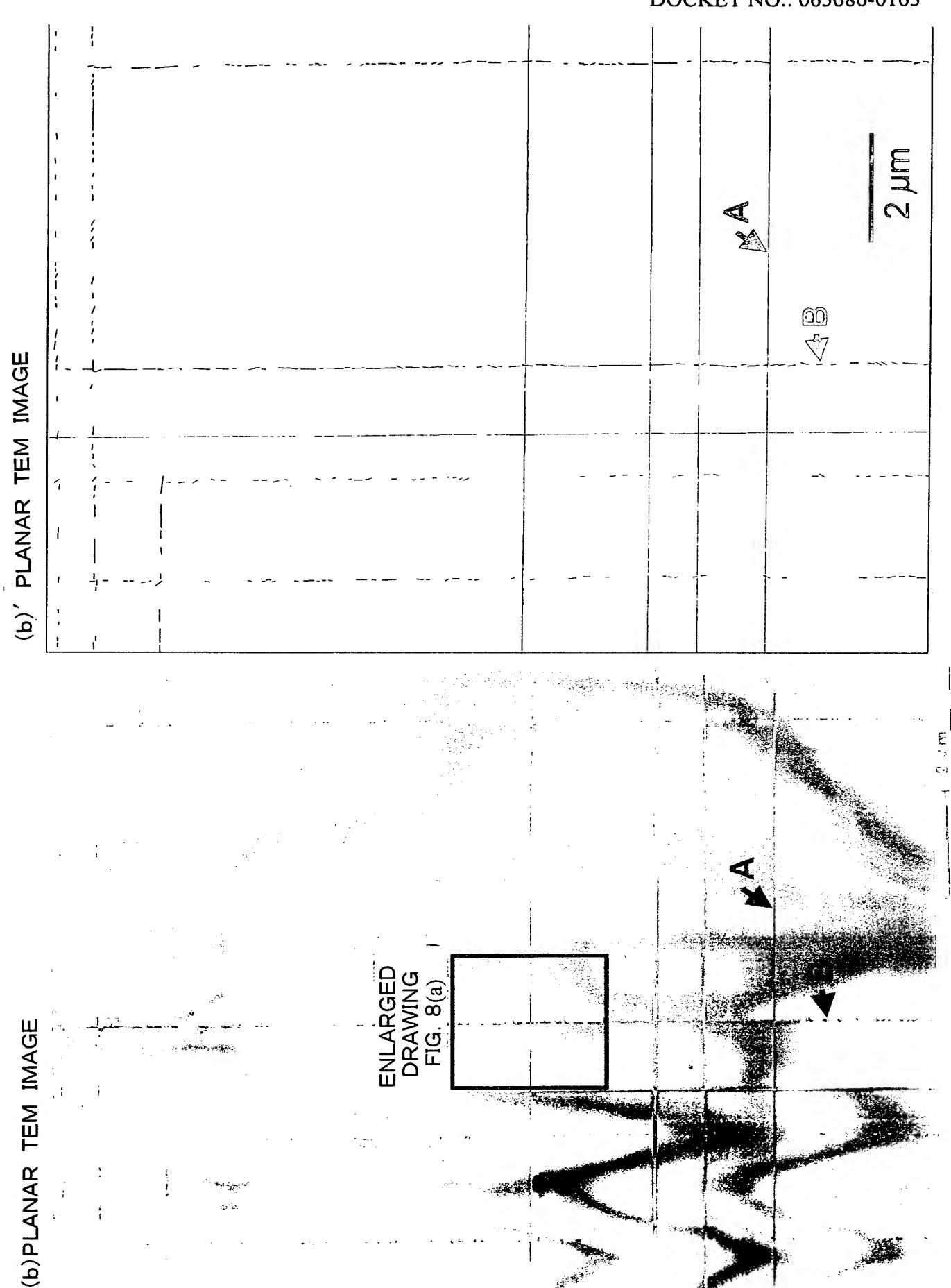
Inventor(s): Kazuya UEJIMA DOCKET NO.: 065686-0163

FIG. 24



Inventor(s): Kazuya UEJIMA DOCKET NO.: 065686-0163

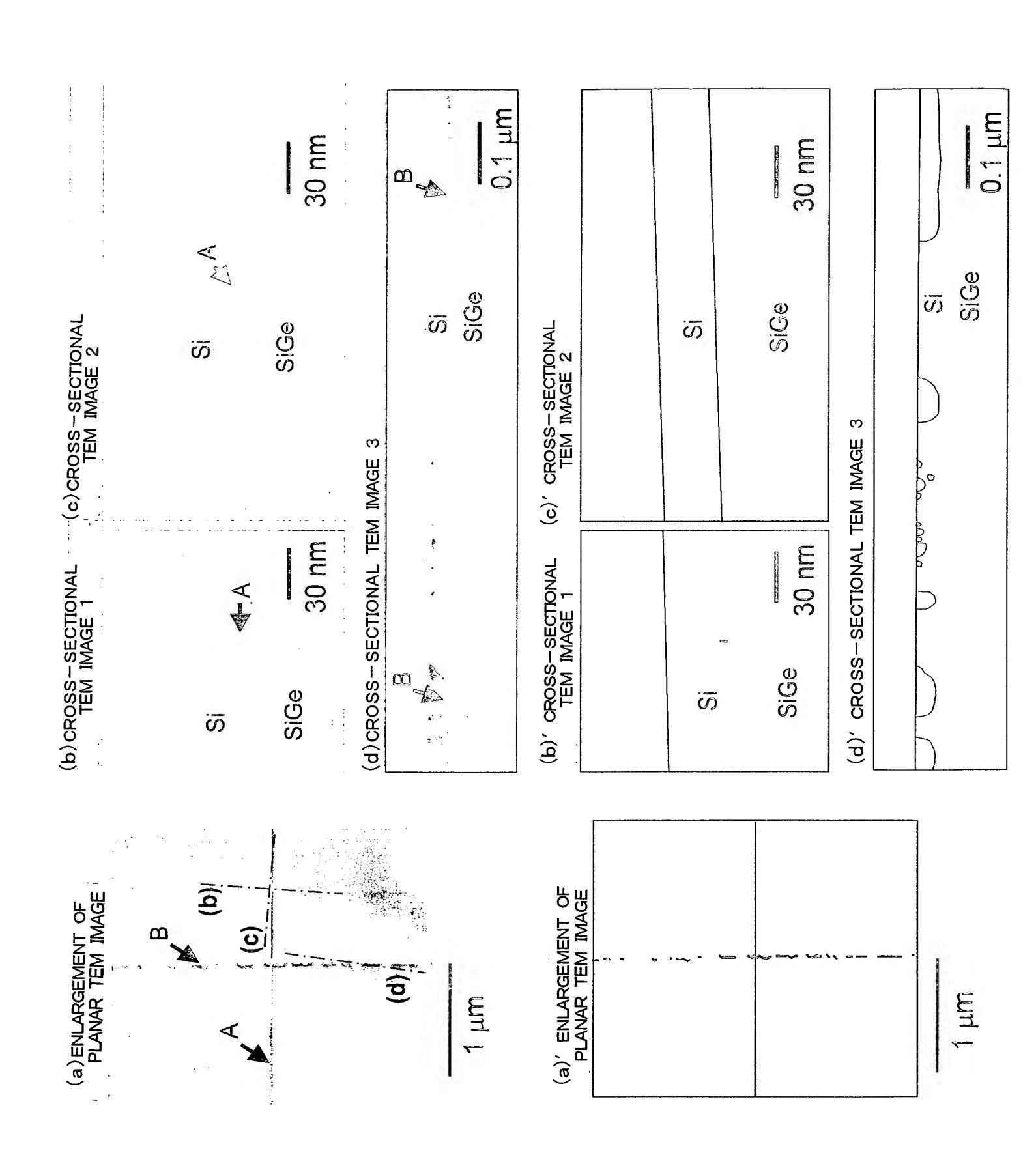
FIG. 24 CONTINUE



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**TRANSISTOR** 

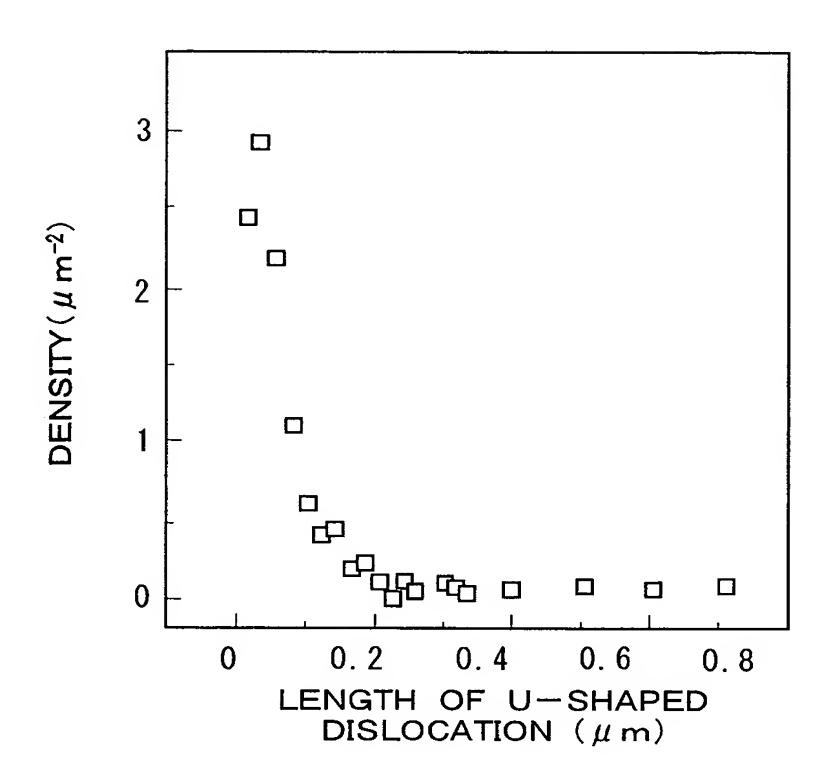
FIG. 25



Title: MIS-TYPE FIELD-EFFECT

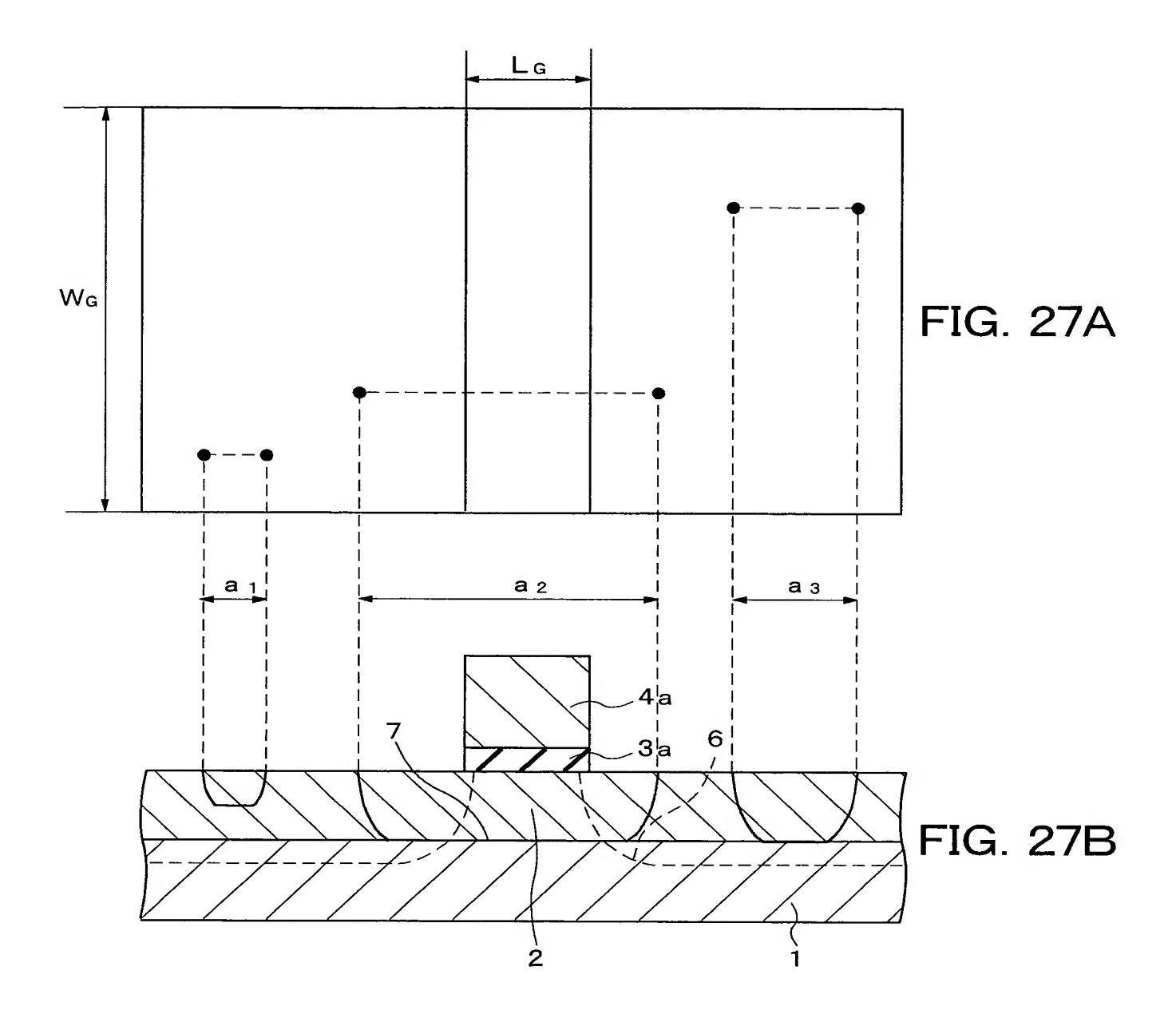
TRANSISTOR

FIG. 26



THE: MIS-TYPE FIELD-EFFECT

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Inventor(s): Kazuya UEJIMA
DOCKET NO.: 065686-0163



Title: MIS-TYPE FIELD-EFFECT

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FIG. 28

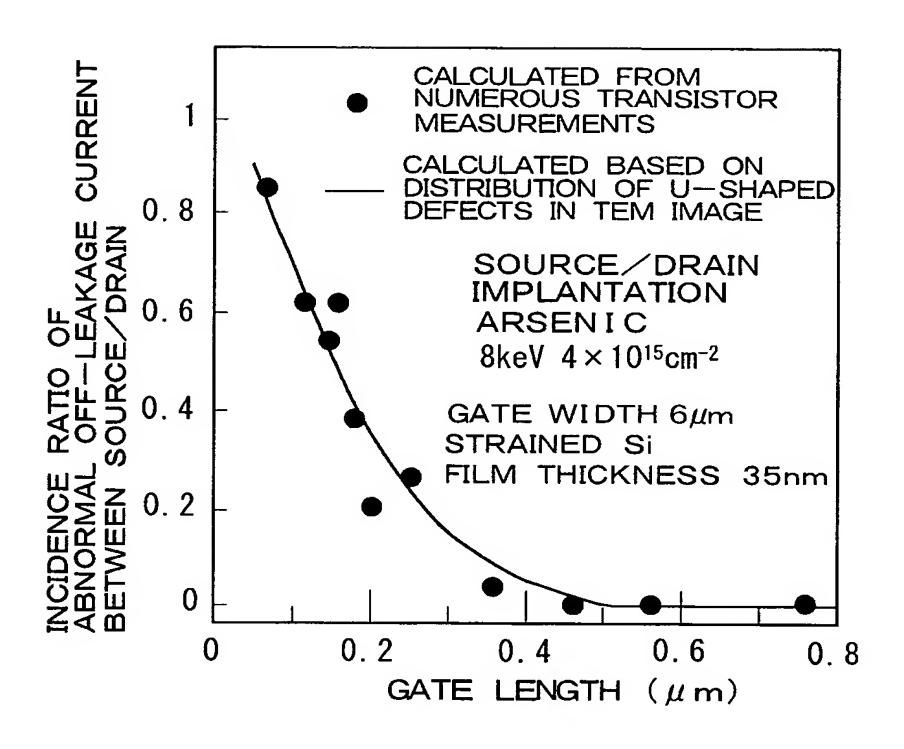
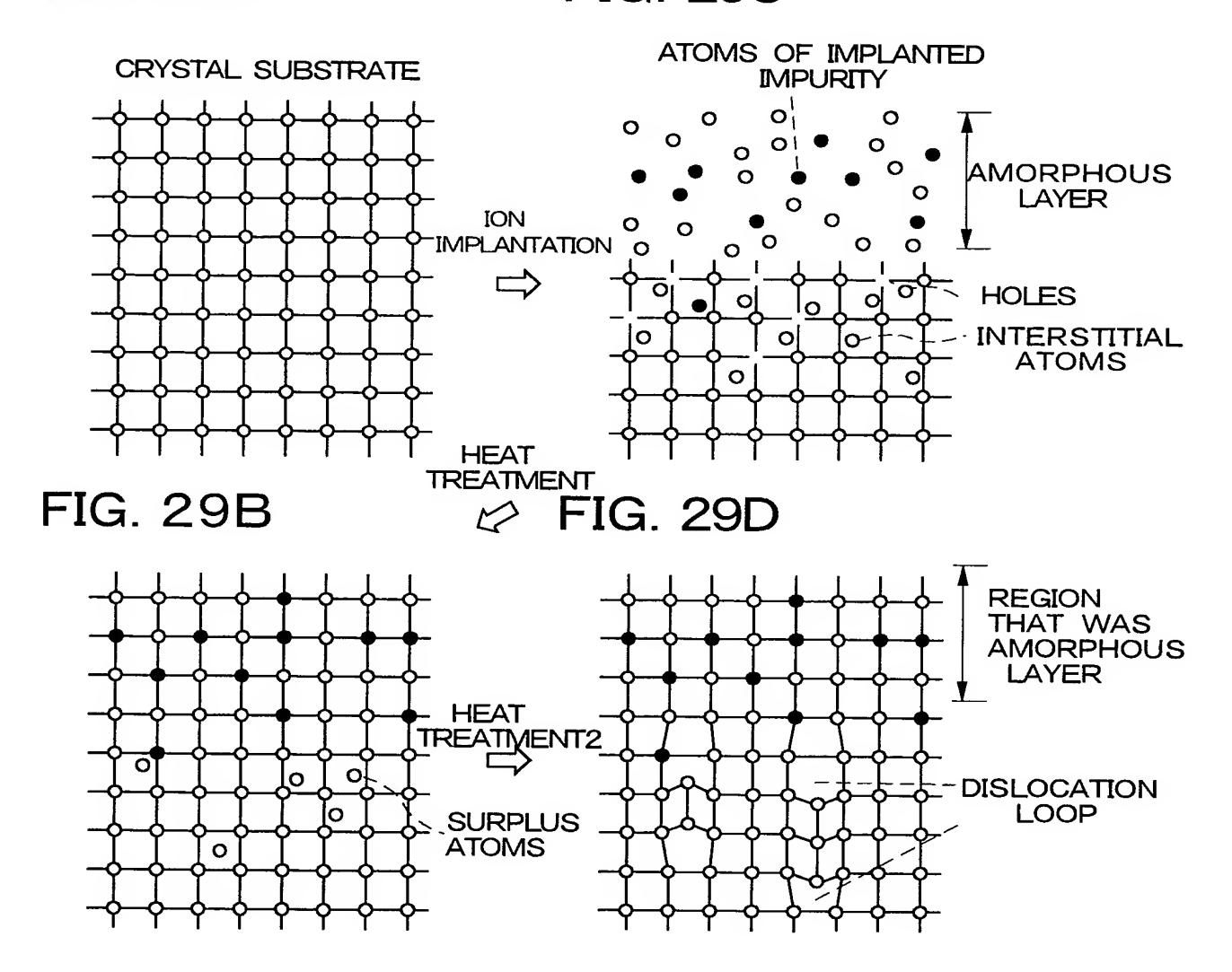


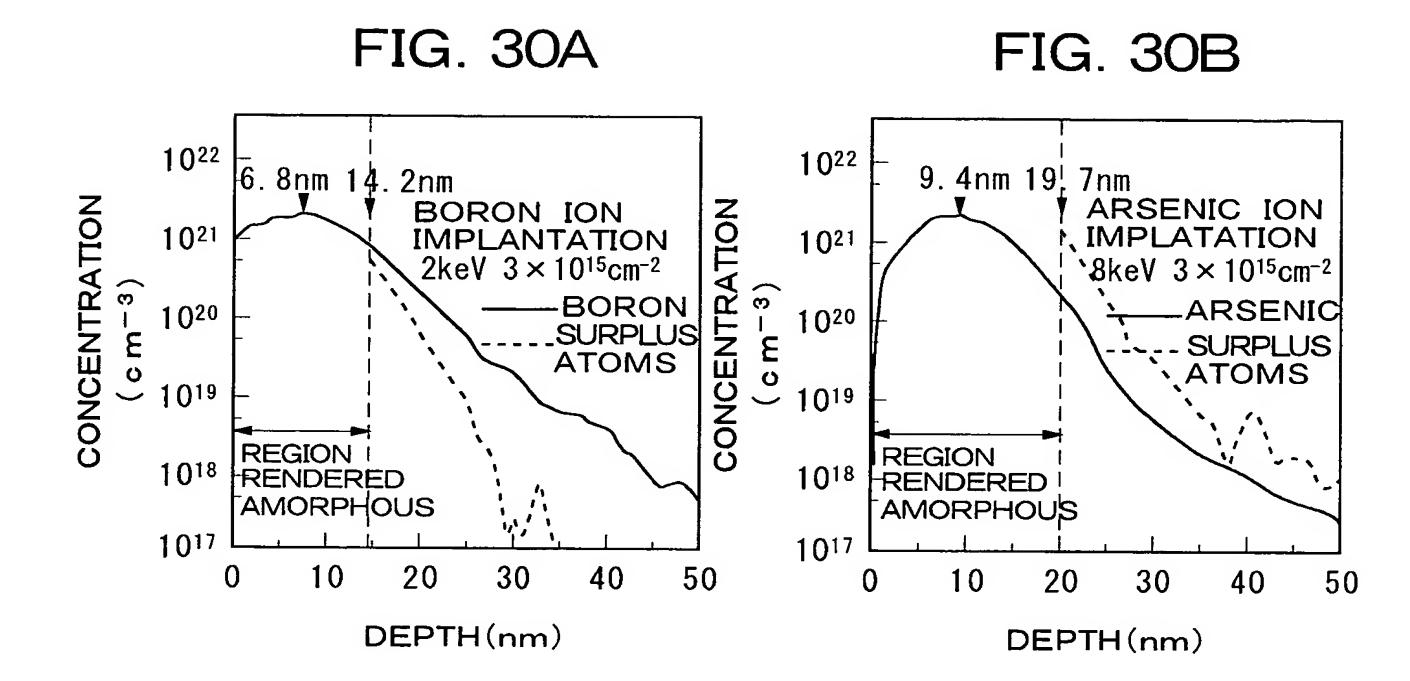
FIG. 29A

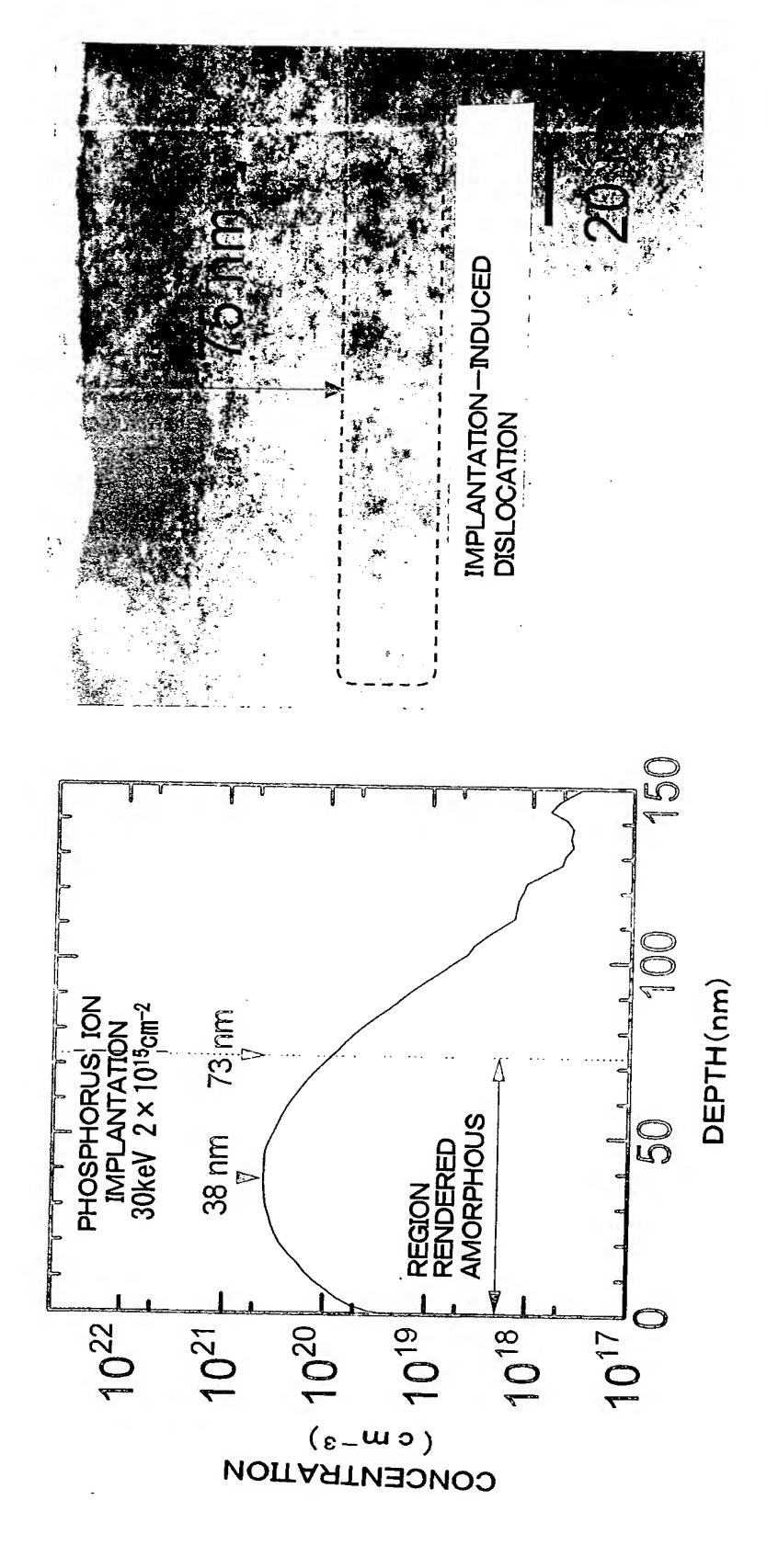
FIG. 29C



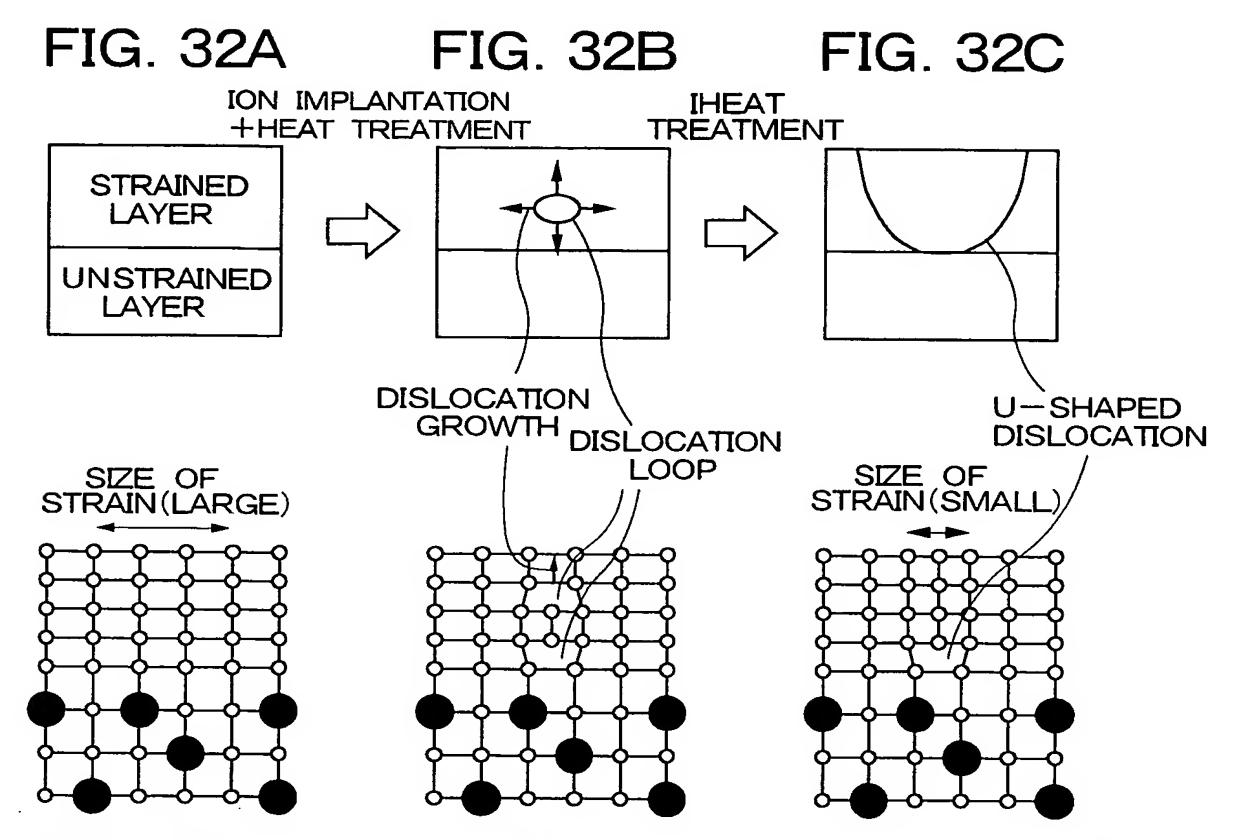
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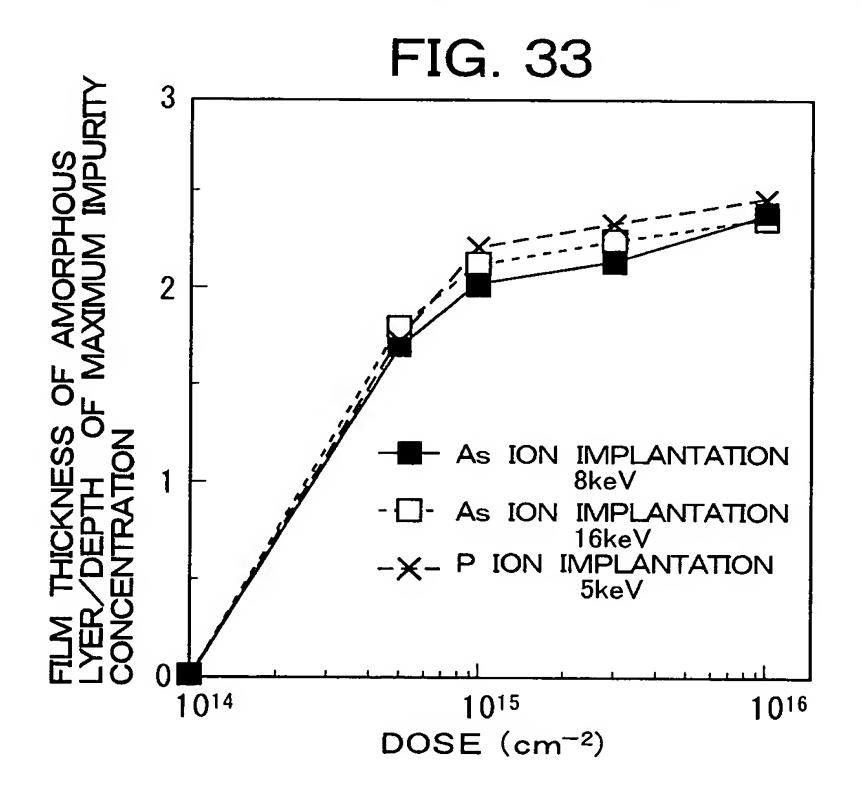


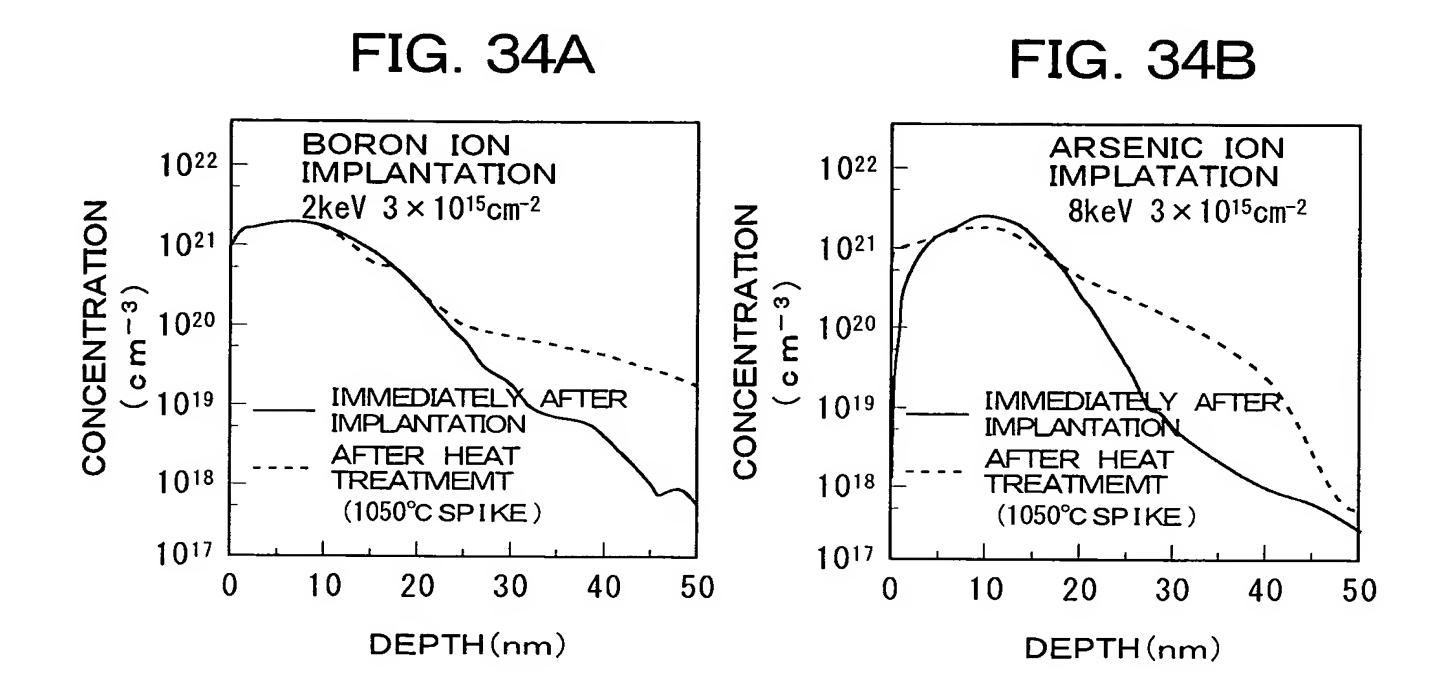


Inventor(s): Kazuya UEJIMA DOGKET NO.: 065686-0163



LOWER DIAGRAMS ARE SCHEMATIC VIEWS OF UPPER DIAGRAMS WHEN THE UPPER DIAGRAMS ARE VIEWED DIRECTLY FROM THE SIDE





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### TRANSISTOR

FIG. 35A

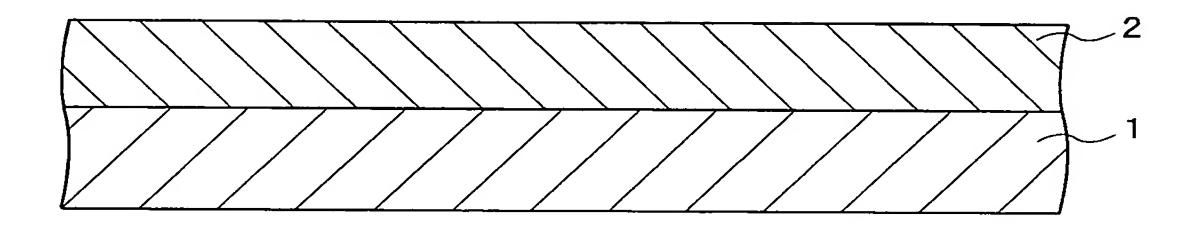


FIG. 35B

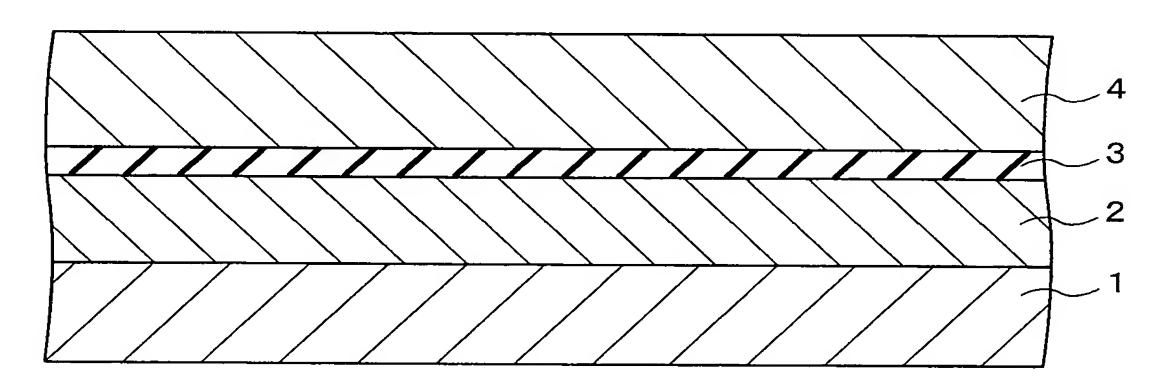
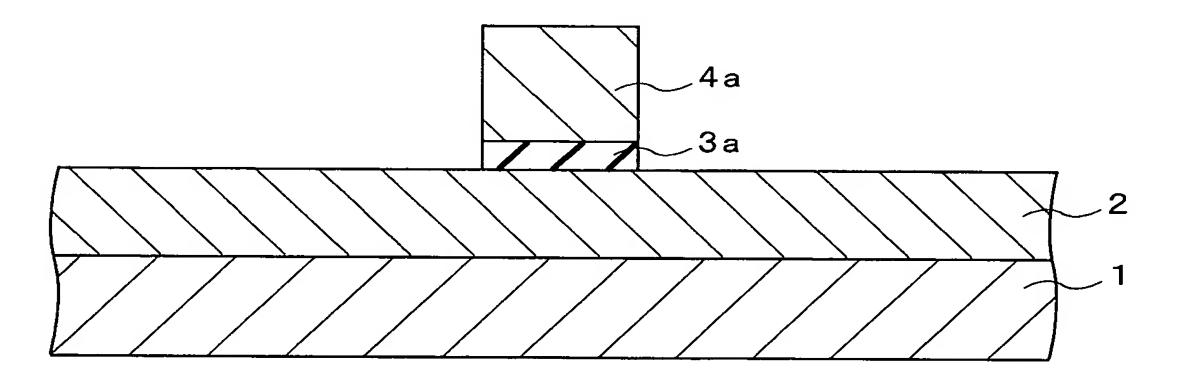


FIG. 35C



The: MIS-1 YEE FIELD-EFFECT

### TRANSISTOR

FIG. 36A

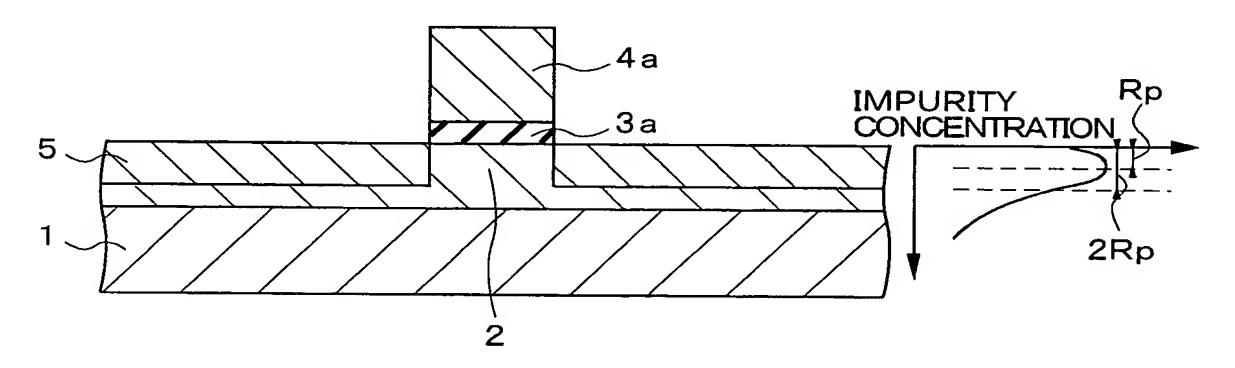


FIG. 36B

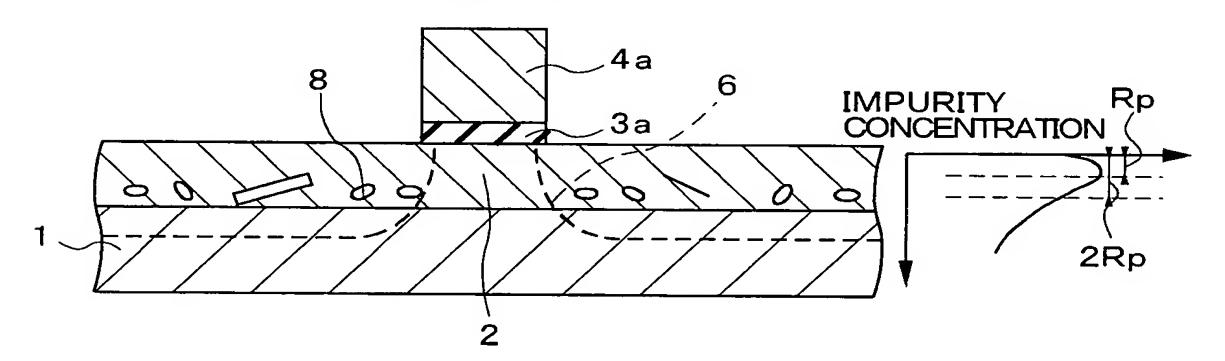
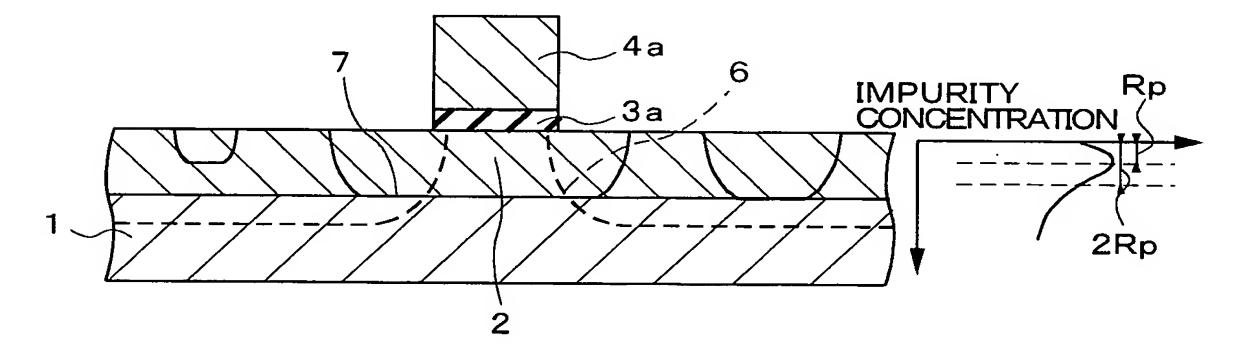


FIG. 36C



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